

General Standards Corporation
High Performance Bus Interface Solutions

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CCVPX-16AI32SSC1M

**32-CHANNEL DIFFERENTIAL 16-Bit,
SIMULTANEOUS SAMPLING,
CONDUCTION-COOLED 3U VPX ANALOG INPUT BOARD**

*With 1MSPS Sample Rate per Channel,
Low Latency Access, Time Tagging,
and Front-Panel I/O*

REFERENCE MANUAL

--- PRELIMINARY DRAFT ---

CCVPX-16Al32SSC1M Preliminary

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SECTION 1.0

INTRODUCTION

1.1 General Description

The CCVPX-16AI32SSC1M board is a single-width conduction-cooled 3U module that provides high-speed simultaneous 16-bit analog input capability for VPX applications. 32 differential analog input channels can be digitized simultaneously at rates up to 1,000,000 conversions per second per channel, with software-controlled voltage ranges of $\pm 10V$, $\pm 5V$, $\pm 2.5V$ or $\pm 1.25V$. Integrated standard functions include Time-Tagging and Low-Latency access. The board is functionally compatible with the IEEE PCI Express bus specification Revision 1.0a.

On-demand autocalibration ensures maximum accuracy under all conditions. A selftest switching network routes calibration reference signals to each channel, and permits board integrity to be verified by the host.

Power requirements consist of +3.3V and +12V from the Host bus in compliance with the PCI Express specification, and operation over the specified temperature range is achieved with conventional air cooling. Specific details of physical characteristics and power requirements are contained in the CCVPX-16AI32SSC1M product specification. Figure 1.1-1 shows the physical configuration of the board and the arrangement of major components.

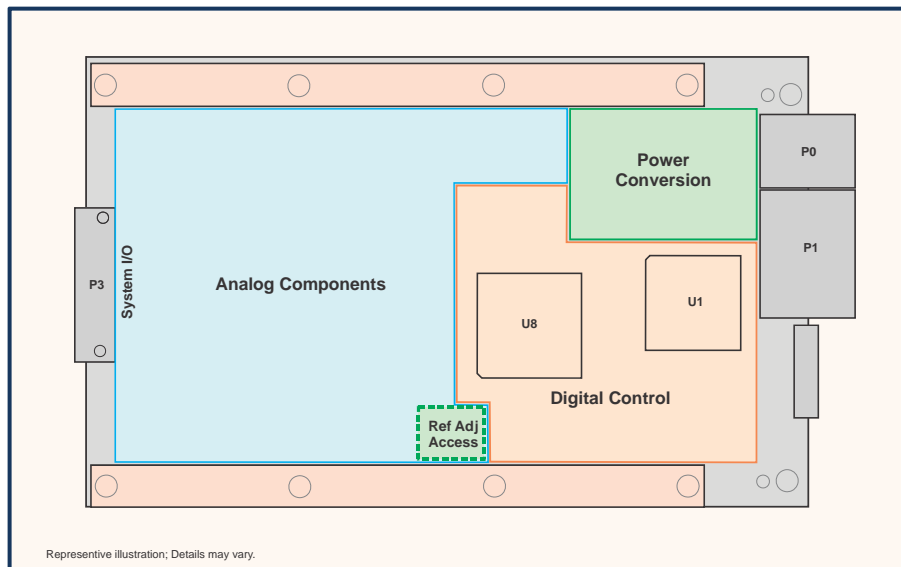


Figure 1.1-1. Physical Configuration

This product is designed for minimum off-line maintenance, and includes internal monitoring and autocalibration features that eliminate the need for disconnecting or removing the module from the system for calibration. System input and output connections are made through a high-density front-panel I/O connector. An auxiliary connector on Side-2 of the board provides bidirectional external sync and clock ports for internal multisite synchronization.

1.2 Functional Overview

Each input channel contains a dedicated successive-approximation (SAR) ADC, the sampled data from which is error-corrected and routed to the PCI Express bus through a 1-MByte FIFO buffer. The 32-Bit local data path supports full D32 local-bus data packing. Operational parameters are software configurable.

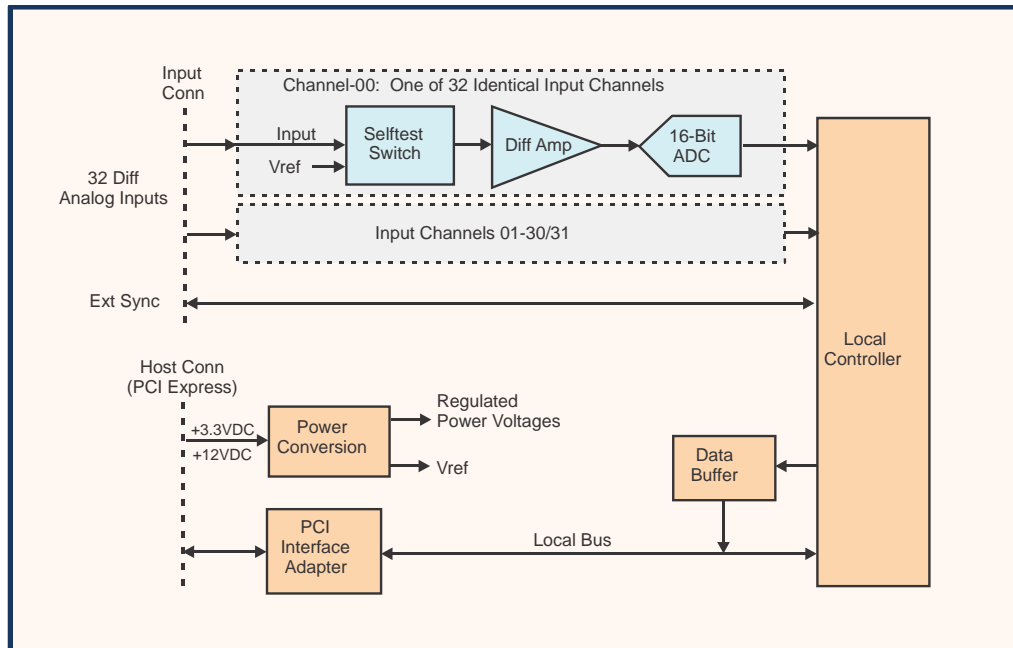


Figure 1.2-1. Functional Organization

Inputs can be sampled in groups of 2, 4, 8, 16, or 32 channels; or any contiguous channel group can be designated for acquisition. The sample clock can be generated from (a) an internal rate generator, (b) by software or (c) by external hardware. Input ranges are software-selectable as $\pm 10V$, $\pm 5V$, $\pm 2.5V$ or $\pm 1.25V$. A time-tag feature permits input data to be referenced to 1-microsecond time base, and selectable low-latency provides access to the most current input data through dedicated readback registers.

An on-demand autocalibration feature determines offset and gain correction values for each input channel, and applies the corrections subsequently during acquisition.

SECTION 2.0

INSTALLATION AND MAINTENANCE

2.1 Board Configuration

This product has no field-alterable configuration features, and is completely configured at the factory for field use.

2.2 Installation

2.2.1 Physical Installation

To minimize the opportunity for accidental damage before installation, the board should be stored in the original protective shipping envelope. System power must be turned OFF before proceeding with the installation.

CAUTION: This product is susceptible to damage from electrostatic discharge (ESD). Before removing the board from the conductive shipping envelope, ensure that the work surface, the installer and the host board have been properly discharged to ground.

Before removing the board from the protective shipping envelope, select an empty 6U expansion slot in the host computer and, if a blank panel is located in the slot position, remove the panel. Then remove the board from the shipping envelope and insert the board into the allocated expansion slot, carefully pressing the board firmly to seat the rear-panel connectors. Secure the panel latches to complete the installation.

2.2.2 Input/Output Cable Connections

System I/O connections are made through the 85-Pin front-panel system I/O connector (Figure 2.2-1), with the pin assignments listed in Table 2.2-1. An acceptable mating connector for system cabling is Omnetics # MNPO-85-DD-N-EJS-C. Contact Sales for custom cables.

Auxiliary Sync I/O connections are made through a low-profile 6-Pin connector located on the back of the board (Side-2), with the pin assignments shown in Table 2.2-2. The auxiliary sync I/O connector is designed to mate with a Molex cable connector Model 51146-0600.

Table 2.2-1. System I/O Connector Pin Functions

Pin	Signal	Pin	Signal
43	INPUT RTN	---	---
42	INPUT RTN	85	INPUT RTN
41	INP 00 LO	84	INP 00 HI
40	INP 01 LO	83	INP 01 HI
39	INP 02 LO	82	INP 02 HI
38	INP 03 LO	81	INP 03 HI
37	INP 04 LO	80	INP 04 HI
36	INP 05 LO	79	INP 05 HI
35	INP 06 LO	78	INP 06 HI
34	INP 07 LO	77	INP 07 HI
33	INPUT RTN	76	INPUT RTN
32	INP 08 LO	75	INP 08 HI
31	INP 09 LO	74	INP 09 HI
30	INP 10 LO	73	INP 10 HI
29	INP 11 LO	72	INP 11 HI
28	INP 12 LO	71	INP 12 HI
27	INP 13 LO	70	INP 13 HI
26	INP 14 LO	69	INP 14 HI
25	INP 15 LO	68	INP 15 HI
24	INPUT RTN	67	INPUT RTN
23	INP 16 LO	66	INP 16 HI
22	INP 17 LO	65	INP 17 HI
21	INP 18 LO	64	INP 18 HI
20	INP 19 LO	63	INP 19 HI
19	INP 20 LO	62	INP 20 HI
18	INP 21 LO	61	INP 21 HI
17	INP 22 LO	60	INP 22 HI
16	INP 23 LO	59	INP 23 HI
15	INPUT RTN	58	INPUT RTN
14	INP 24 LO	57	INP 24 HI
13	INP 25 LO	56	INP 25 HI
12	INP 26 LO	55	INP 26 HI
11	INP 27 LO	54	INP 27 HI
10	INP 28 LO	53	INP 28 HI
9	INP 29 LO	52	INP 29 HI
8	INP 30 LO	51	INP 30 HI
7	INP 31 LO	50	INP 31 HI
6	INPUT RTN	49	INPUT RTN
5	DIG RTN	48	DIG RTN
4	DIG RTN	47	CLOCK RST INP
3	DIG RTN	46	REF CLK INP
2	DIG RTN	45	CLOCK I/O ¹ or SAMP CLK INP ²
1	DIG RTN	44	SYNC I/O ¹ or SAMP CLK OUT ²

¹ Default configuration. Not software-configured for time tagging.² If software-configured for time tagging.

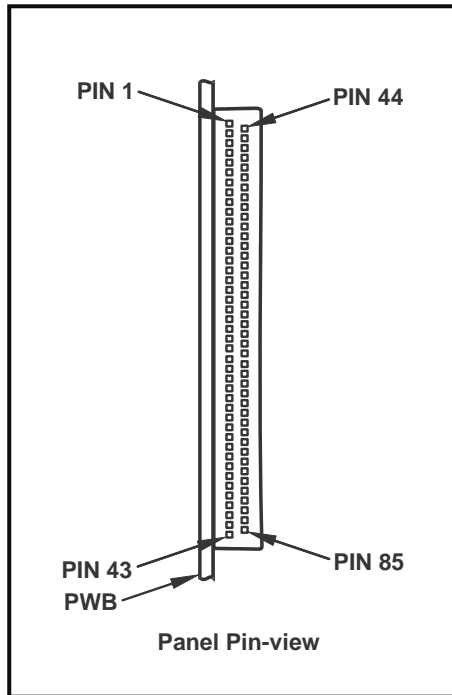


Figure 2.2-1. System I/O Connector

System I/O Mating Connector:

Omnetics # MNPO-85-DD-N-EJS-C,
dual-row, straight tail.
(Assembled cables available)

Table 2.2-2. Auxiliary Sync I/O Connections

SYNC-I/O CONN PIN ¹	SIGNAL
1	DIG RTN
2	AUX CLOCK
3	DIG RTN
4	AUX SYNC
5	DIG RTN
6	Reserved. Connect to INPUT RTN or leave disconnected.

¹ Recommended Sync-I/O mating cable connector is: Molex# 51146-0600.

2.3 System Configuration

2.3.1 Analog Inputs

The 32 analog input channels can be configured for either differential or single-ended operation. This configuration is determined by external wiring as shown in Figure 2.3-1, and is not affected by application software.

2.3.1.1 Differential Inputs

Differential input operation usually provides the best performance, and is essential when the input signal sources are not isolated from each other or have returns that are at significantly different potentials. A potential difference between grounds is significant if it is larger than the maximum tolerable measurement error.

This operating mode also offers the highest rejection of the common mode noise, which is a characteristic of long cables in typical instrumentation environments. When operating in the differential mode (Figure 2.3-1a), the wire pair from each signal source is connected between the HI(+) and LO(-) inputs of a single input channel. The input return (INPUT RTN in Table 2.2-1) is connected to a ground point which must ensure that the sum of the signal level (**V_{sig}**) and the common mode voltage (**V_{cm}**) remain within the range specified for the board. Ground current through the INPUT RTN pins must be limited in order to avoid damage to the cable or the input board.

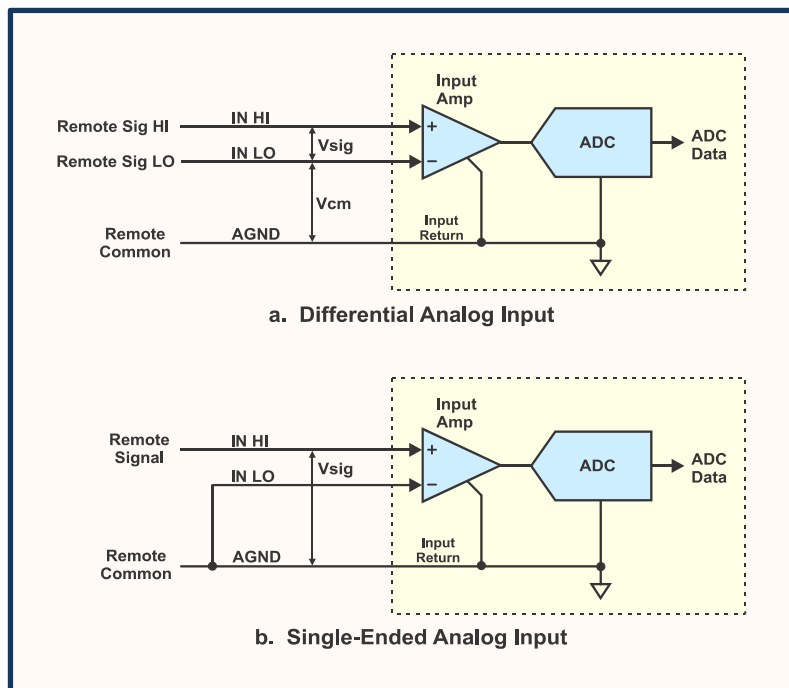


Figure 2.3-1. Analog Input Configurations

2.3.1.2 Single-Ended Inputs

Single-ended operation (Figure 2.3-1b) generally provides acceptable performance only when the input signal sources either are isolated from each other, or are common to a single isolated signal return. A single-ended configuration usually is more susceptible to system interference than a differential configuration.

Single-ended inputs share a common input return that provides a return path for all inputs, making isolation from other system grounds a critical issue. If the signal sources are returned externally to system ground when operating in this mode, a potential difference between the system ground and input return can cause erroneous measurements, or could generate potentially destructive ground current.

For applications in which multiple signal sources share a single ground reference or return, the differential configuration is recommended, with all "LO" inputs connected together at the common remote return.

2.3.2 External Clock and Sync I/O

External clocking and synchronization behavior depends upon whether or not Time-Tagging (Appendix-C) is selected:

Time Tagging selected (Appendix C):

The CLOCK RST INP, REF CLK-INP, SAMP CLK INP and SAMP CLK OUT I/O pins function as described in Appendix C.

Time Tagging not selected:

The CLOCK RST INP and REF CLK INP I/O pins are nonfunctional and should be grounded, while the CLOCK I/O and SYNC I/O pins function as described here.

The CLOCK I/O and SYNC I/O pins in the I/O connector are bidirectional TTL signals that provide external control of analog input sampling and burst triggering. These signals are referenced to the DIG RTN pin, which is connected internally to PCI Express digital ground.

When configured as inputs by selection of the target mode, these pins accept clock and triggering signals from any external TTL source, including those originating on another CCVPX-16AI32SSC1M. For boards configured as initiators, the clock and sync pins become outputs that can be used to control external devices, including other CCVPX-16AI32SSC1M boards. Loading of initiator outputs should not exceed 10 milliamps. In the default state after power-up or initialization, both pins are configured as inputs. Clock and sync pins default to inputs (targets), and are pulled up internally to +3.3V through 33K-Ohms.

NOTE: The logic polarities of the clock and sync I/O pins can be inverted by application software.

2.3.2.1 External ADC Clocking

When the CLOCK I/O pin is configured as an input, all active input channels are sampled on the falling edge of a TTL input signal on this pin. Both the HIGH and LOW states of the clock input must have minimum durations of 100ns.

When configured as an initiator, the CLOCK I/O pin becomes a normally HIGH output that falls for 120-180ns at each occurrence of the internal ADC sample clock.

2.3.2.2 External Burst Triggering

When the SYNC I/O pin is configured as an input, a high-to-low TTL transition on this pin can be used to trigger an internal acquisition burst. Both HIGH and LOW sync input states must have durations of 100ns.

When configured as an initiator, the SYNC I/O pin becomes a normally HIGH output that falls for 120-180ns at the initiation of each internal triggered burst.

2.3.3 Auxiliary External Clock and Sync I/O

Two auxiliary external connections provide an alternate method of synchronizing sample clocking to external events. These TTL connections are available as AUX-CLOCK and AUX-SYNC (Table 2.2-2), and are accessible through a low-profile 6-Pin connector on the edge of the board.

The AUX I/O pins can be programmed to be asserted either HIGH or LOW, and can be configured individually as inputs or outputs. Active AUX *outputs* produce an output pulse for each internal ADC sample clock or burst trigger. Source and sink load capacity of each output is 8 milliamps. Further details pertaining to these I/O functions are described in Section 3.9.

2.3.4 Multiboard Synchronization

If multiple boards are to be synchronized together, the CLOCK I/O and/or the SYNC I/O pins from one board, the *initiator*, are connected to the corresponding pins of one or more *target* boards (Figure 2.3-2). The controlling software determines specific clocking and burst triggering functions. The maximum number of targets depends upon both static loading and cable characteristics, and can vary typically from four to as many as eight.

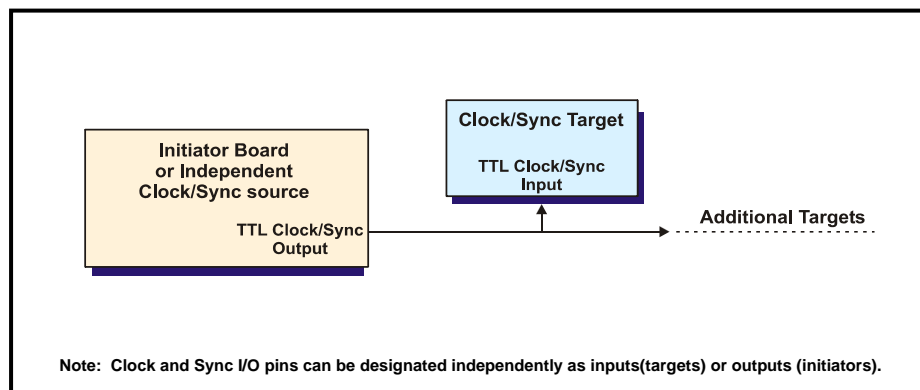


Figure 2.3-2. Multiboard Synchronization

2.4 Maintenance

This product requires no scheduled hardware maintenance other than periodic reference verification and possible adjustment. The optimum verification interval will vary, depending upon the specific application, but in most instances an interval of one year is sufficient.

In the event of a suspected malfunction, all associated system parameters, such as power voltages, control bus integrity, and system interface signal levels, should be evaluated before troubleshooting of the board itself is attempted. A board that has been determined to be defective should be returned to the factory for detailed problem analysis and repair.

2.5 Reference Verification

All analog input channels are software-calibrated to a single internal voltage reference by an embedded autocalibration firmware utility. The procedure presented here describes the verification and adjustment of the internal reference.

2.5.1 Equipment Required

Table 2.5-1 lists the equipment required for verifying or adjusting the internal reference. Alternative equivalent equipment may be used.

Table 2.5-1. Reference Verification Equipment

EQUIPMENT DESCRIPTION	MANUFACTURER	MODEL
Digital Multimeter, 5-1/2 digit, 0.005% accuracy for DC voltage measurements at ± 10 Volts.	Hewlett Packard	34401A
Host chassis with available 3U VPX slot	(Existing host)	---
3U VPX Extender card (Optional)	---	---
Test cable; suitable for connecting the digital multimeter to two 0.02-inch square test posts.	---	---

2.5.2 Verification and Adjustment

The following procedure describes the verification of the single reference voltage that ensures conformance to the product specification. Adjustment of the internal reference, if necessary, is performed with an internal trimmer that is accessible as shown in Figure 1.1-1.

This procedure assumes that the board to be adjusted is installed in an operational host:

1. Connect the digital multimeter between VCAL (+) Pin-3, and REF RTN (-) Pin-4 in the J4 test connector.
2. If power has been removed from the board, apply power now. Wait at least 10 minutes after power is applied before proceeding..
3. Select the $\pm 10\text{V}$ input range.
4. Verify that the digital multimeter indication is $+9.9900\text{ VDC} \pm 0.0008\text{ VDC}$. If the indication is not within this range, adjust the INTERNAL REFERENCE trimmer accordingly.
5. Verification and adjustment is completed. Remove all test connections.

SECTION 3.0

CONTROL SOFTWARE

3.1 Introduction

The CCVPX-16AI32SSC1M is compatible with the IEEE PCI Express Specification revision 1.0a. A PLX™ PEX-8311 adapter operating in J-mode controls the interface. Configuration-space registers are initialized internally to support the location of the board on any 128 long-word boundary in memory space. After initialization has been completed, communication between the PCI Express bus and the local bus takes place through the control and data registers shown in Table 3.1-1. All local data transfers are long-word D32. Specific operational conditions identified throughout this section can invoke a single interrupt request from the board. DMA access is supported for data transfers from the analog input data buffer. The board identifies itself over the PCI Express bus with device, vendor and subsystem identification codes that are available from General Standards.

Table 3.1-1. Control and Data Registers

Offset (Hex) ¹	Register	Access Mode ²	Default	Primary Function	Para Ref
0000	BOARD CONTROL (BCR)	RW	0000 4070h	Board Control Register (BCR)	3.2
0004	INTERRUPT CONTROL	RW	0000 0008h	Interrupt conditions and flags	3.7
0008	INPUT DATA BUFFER	RO	XXXX XXXXh	Analog input data buffer	3.5.2
000C	INPUT BUFFER CONTROL	R/W	0003 FFEh	Input buffer threshold and control	
0010	RATE-A GENERATOR	RW	0001 0500h	Rate-A generator freq selection	3.4.4
0014	RATE-B GENERATOR	RW	0000 2000h	Rate-B generator freq selection	
0018	BUFFER SIZE	RO	0000 0000h	Number of values in the input buffer	3.5.2
001C	BURST SIZE	R/W	0000 0001h	Number of sample clocks in a triggered burst.	3.12.1
0020	SCAN AND SYNC CONTROL	R/W	0000 0005h	Channels per scan; Clock and Sync sources.	3.4.2
0024	ACTIVE CHANNEL ASSIGNMENT	R/W	0000 0100h	Specific first and last active channels.	3.4.2.2
0028	BOARD CONFIGURATION	RO	00XX XXXXh	Firmware revision and option straps.	3.10
002C	Autocal Values ³	R/W	0000 080Xh	Autocal value readback.	---
0030	Auxiliary R/W Register ³	R/W	0000 0000h	Auxiliary register. For internal use only.	---
0034	AUXILIARY SYNC I/O CONTROL	R/W	0000 0000h	Controls the auxiliary sync I/O port	3.9
0038	SCAN MARKER UPPER WORD	R/W	0000 0000h	Packed-data scan marker D[31..16].	3.11
003C	SCAN MARKER LOWER WORD	R/W	0000 0000h	Packed-data scan marker D[15..0].	
0040	Low Latency Control	R/W	0000 07C0h	Low Latency hold and release channels	3.14
0044-004C	(Reserved)	RO	0000 0000h	---	---
0050-00FC	Time Tag register field	---	---	---	App-C
0100-17C	Low-Latency Data	RO	0000 XXXXh	Low Latency data	3.14
0180-1FC	(Reserved)	RO	---	---	---

¹ Offsets from the PCI base address for local addressing.

² R/W = Read/Write; RO = Read-Only.

³ Maintenance register. Shown for reference only.

3.2 Board Control Register (BCR)

The Board Control Register (BCR) controls primary board functions, including the analog input mode and voltage range. Table 3.2-1 provides a brief description of each bit field in the BCR, as well as indicating an associated section in the text.

Table 3.2-1. Board Control Register (BCR)

Offset: 0000h

Default: 0000 4070h

Bit	Mode	Designation	Def	Description	Para Ref
D00-D02	R/W	AIM[2..0]	0	Analog input mode. Selects system inputs or selftest mode. Defaults to System Inputs	3.5.3.1
D03	R/W	(Reserved)	0	---	---
D04-D05	R/W	RANGE[1..0]	3h	Analog input range. Defaults to $\pm 10V$ range.	3.4.1
D06	R/W	OFFSET BINARY	1	Selects offset-binary analog I/O data format when asserted HIGH, or two's complement when LOW.	3.5.1.2
D07-D9	R/W	(Reserved)	0h	---	---
D10	RO	DATA ON HOLD	0	Low-Latency access status flag.	3.14
D11	R/W	DISABLE SCAN MARKER	0	Disables the scan marker in data packing mode.	3.11
D12	R/W	*INPUT SYNC	0	Produces a single ADC clock when selected in the Scan and Sync Control Register, or a single burst trigger when selected with the Burst On Sync control field.	3.12
D13	R/W	*AUTOCAL	0	Initiates an autocalibration operation when asserted.	3.6
D14	RO	AUTOCAL PASS	1	Set HIGH at reset or autocal initialization. A HIGH state after autocal completion confirms a successful calibration.	
D15	R/W	*INITIALIZE	0	Initializes the board when set HIGH. Sets all register defaults.	3.3
D16	R/W	BUFFER UNDERFLOW	0	Set HIGH if the buffer is read while empty. Cleared by direct write or by buffer clear.	3.5.2
D17	R/W	BUFFER OVERFLOW	0	Set HIGH if the buffer is written to when full. Cleared by direct write or by buffer clear.	
D18	R/W	ENABLE DATA PACKING	0	Enables local-bus data packing	3.11
D19	R/W	(Reserved)	0	---	---
D20	R/W	ENABLE TIME TAG OPERATION	0	Enables time tagging operations.	c1.1
D21-D31	RO	(Reserved)	0	---	---

* Clears automatically when the associated operation is completed.

3.3 Initialization

3.3.1 Configuration

During *board configuration*, initial values for both the PCI Express configuration registers and the internal control logic are extracted from internal nonvolatile read-only memory. This process is initiated by a bus reset, and should be required only once after the initial application of power. While the configuration registers are being loaded, the response to target accesses is RETRY's. Configuration operations are executed in the sequence shown in Table 3.3-1. Board configuration terminates with the PCI Express interrupt disabled.

Table 3.3-1. Configuration Operations

Operation	Maximum Duration
PCI Express configuration registers are loaded from internal ROM	3 ms
Internal control logic is configured from internal ROM	300 ms
Internal control logic is initialized	3 ms

3.3.2 Local Controller Initialization

Internal control logic can be initialized without reconfiguration of the PCI Express registers by setting the INITIALIZE control bit in the BCR. This action initializes the internal logic, but does not affect the PCI Express configuration registers and does not reconfigure the internal control logic. Initialization requires 3 milliseconds or less for completion, and produces the following default conditions:

- The BCR is initialized; all defaults are invoked (Table 3.2-1),
- Analog input voltage range is ± 10 Volts (Tables 3.2-1, 3.4-1),
- All available channels are active (Table 3.4-2),
- Input sample clocking is disabled (Tables 3.4-2, 3.4-4),
- Rate-A generator is adjusted for a 50 kHz sample rate, and is disabled (Tables 3.4-4, 3.4-5).
- Analog input data coding format is offset binary; Data packing is disabled (Table 3.5-2),
- The analog input buffer is reset to empty (Tables 3.5-3, 3.5-4),

Upon completion of initialization, the INITIALIZE control bit is cleared automatically.

3.4 Analog Input Parameters

3.4.1 Input Voltage Range

BCR control field RANGE[] (Table 3.4-1) selects the analog input voltage range.

Table 3.4-1. Analog Voltage Range Selection

Range Select[1:0]	Analog Input Range
0	$\pm 1.25V$
1	$\pm 2.5V$
2	± 5 Volts
3	± 10 Volts

3.4.2 Active Channel Selection

NOTE: The Scan and Sync control register (Table 3.4-2) controls the selection of active channels, as well as the configuration of internal timing signals.

3.4.2.1 Predetermined Channel Group

The analog inputs can be sampled in groups of 2, 4, 8, 16 or 32 active channels, or any single channel can be selected for digitizing. The number of active channels is selected by the ACTIVE CHANNELS[] field in the scan and sync control register. Each active channel group commences with Channel-00, and proceeds upward through successive channels to the selected number of channels.

For Single-Channel sampling (ACTIVE CHANNELS[] = 0), the channel to be digitized is selected by the SINGLE-CHANNEL SELECT control field.

Table 3.4-2. Scan and Sync Control Register

Offset: 0020h

Default: 0000 0005h

Bit	Mode	Designation	Def	Description
D00-D02	R/W	ACTIVE CHANNELS	5h	Number of active input channels: 0 => Single-Channel mode * 1 => 2 channels (00-01) 2 => 4 channels (00-03) 3 => 8 channels (00-07) 4 => 16 channels (00-15) 5 => 32 channels (00-31); Default value 6 => (Reserved) 7 => Channel group assignment (See Section 3.4.2.2) * Channel selected by Single-Channel Select field below.
D03-D04	R/W	SAMPLE CLOCK SOURCE	0h	Selects the analog input sample clocking source and I/O mode: 0 => External Clock input line (Selects Clock TARGET mode) 1 => Internal Rate-A generator output 2 => Internal Rate-B generator output 3 => BCR Input Sync control bit (If bursting disabled)
D05	R/W	ENABLE CLOCKING	0	Enables the selected ADC clocking process
D06	R/W	RATE-B SYNC OUTPUT	0	Provides the output of the Rate-B generator as an external output pulse, and drives the Rate-B generator either from the output of the Rate-A generator or from the sample clock. Over-rides the Burst-On-Sync selection. See 3.15.
D07	RO	BURST BUSY	0	Indicates that a triggered burst is in progress.
D08-D09	R/W	BURST ON SYNC	0h	Selects bursting trigger source and I/O mode (Section 3.12) 0 => Bursting disabled 1 => Rate-B generator 2 => External Sync-I/O input (Selects Sync TARGET mode) 3 => BCR Input Sync control bit.
D10	R/W	RATE-B CLOCK SOURCE	0	Selects the clock input source for the Rate-B generator: 0 => Master clock (or Sample Clock; See 3.15). 1 => Rate-A generator output.
D11	R/W	INVERT CLOCK AND SYNC I/O	0	Inverts the logic polarities of external clock and sync I/O input and output signals to assert HIGH.
D12-17	R/W	SINGLE-CHANNEL SELECT	0h	Selects the input channel number when operating in the Single-Channel scanning mode.
D18-D31	RO	(Reserved)	0	Inactive

3.4.2.2 User-Defined Channel Group

If "Channel group assignment" is selected in the ACTIVE CHANNELS field in the Scan and Sync control register (Table 3.4-2), the first and last active channels are defined by the Active Channels Assignment control register shown in Table 3.4-3. The group of active channels is *contiguous*, beginning with the channel designated by the FIRST CHANNEL SELECT field, and proceeding upward through consecutive channels to and including the channel designated by LAST CHANNEL SELECT. The LAST CHANNEL SELECT field must be equal to or greater than the FIRST CHANNEL SELECT field.

When selection of active channels is user-defined, the context of the "Channel-00" tag in the data buffer (Table 3.5-1) changes to the "First-Channel" tag. For example, if FIRST CHANNEL SELECT = 05, then D16 in the buffer will be HIGH for Channel-05 data, and LOW otherwise. This context change applies also to the scan marker if data packing is enabled (Section 3.11).

NOTE: The first channel must not be higher than the selected last channel, and the selected last channel must not exceed the highest available channel number.

Table 3.4-3. User-Defined Active Channel Assignment

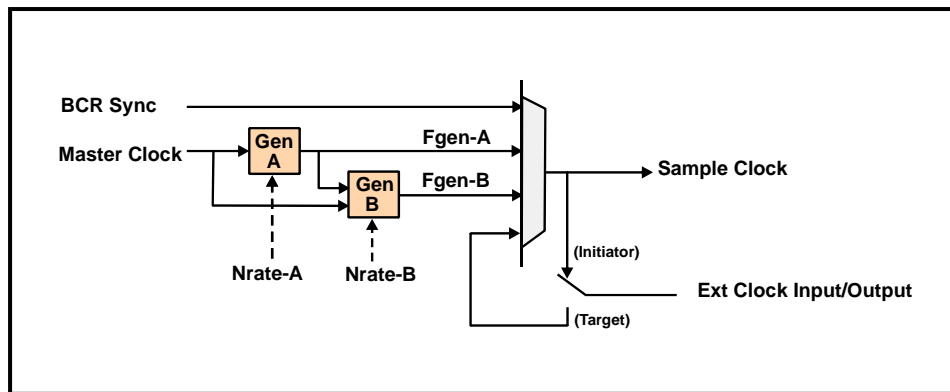
Offset: 0000 0024h

Default: 0000 0100h

Data Bit	Mode	Designation	Default	Description
D00-D07	R/W	FIRST CHANNEL SELECT	0	First (lowest-numbered) active channel
D08-D15	R/W	LAST CHANNEL SELECT	1	Last (highest-numbered) active channel
D16-D31	RO	(Reserved)	0	Inactive. Returns all-zero.

3.4.3 Timing Organization

Figure 3.4-1 illustrates the manner in which ADC timing signals are organized within the board. The input sample clock selector is controlled by the Scan and Sync control register, which provides direct software control of clocking and sync operations. The bidirectional external clock I/O pin provides external control of ADC clocking.

**Figure 3.4-1. Sample Clock Organization**

Two internal rate generators operate directly from the master clock frequency, or can be cascaded. A sample clock can be generated by (a) an internal rate generator, (b) the INPUT SYNC control bit in the BCR, or (c) an external clock source. Each sample clock produces a sample of all active input channels.

NOTE: The logic polarities of the external clock and sync I/O pins can be inverted by setting the INVERT CLOCK AND SYNC I/O control bit HIGH in the Scan and Sync control register (Paragraph 2.3.2 and Table 3.4-2). This inversion does not affect the Auxiliary Clock and Sync logic polarities selected in Table 3.9-1.

3.4.4 Sample Rate Control

All active channels are sampled, or clocked, simultaneously from the source selected by the SAMPLE CLOCK SOURCE control field in the Scan and Sync control register.

NOTE: ADC sampling (clocking), is disabled while the ENABLE CLOCKING control bit is LOW, or is enabled when this bit is set HIGH.

NOTE: If bursting is disabled, a single sample of all inputs can be obtained by asserting the INPUT_SYNC control bit HIGH in the BCR. This bit clears automatically.

3.4.4.1 Sample Rate Generators

Each of two rate generators consists of a 16-bit down-counter that divides the master clock frequency by a 16-bit integer contained in the associated rate control register. The two rate control registers are organized as shown in Table 3.4-4. Bits D00-D15 represent the frequency divisor **Nrate**, and D16 disables the associated generator when set HIGH. D16 defaults to the HIGH (disable) state in the Rate-A control register.

Table 3.4-4. Rate Generator Control Register

Offset: 0010h (Rate-A), 0014h (Rate-B)

Default: 0001 0500h (Rate-A), 0000 2000h (Rate-B)

Data Bit	Mode	Designation	Default	Description
D00-D15	R/W	NRATE	---	Rate generator frequency control
D16	R/W	GENERATOR DISABLE	1	Disables the rate generator when HIGH
D17-D31	RO	(Inactive)	0	---

3.4.4.2 Rate Generator Frequency Control

Each rate generator is controlled by a *divisor* **Nrate** that can be adjusted up to a maximum value of FFFFh (65535 decimal). With a master clock frequency of **Fclk**, the output frequency **Fgen** of each generator is determined as:

$$\mathbf{Fgen\ (Hz)\ =\ Fclk\ (Hz)\ /\ Nrate,}$$

where **Nrate** is the decimal equivalent of D00-D15 in the rate generator control register. **Fgen** is the sampling frequency, and equals the rate at which all active channels are sampled. **Fclk** has a standard value of **64 MHz**, but may have other values depending upon custom ordering options.

The maximum sampling frequency **Fgen-max** is **1.0 MHz**.

Table 3.4-5. Rate Generator Frequency Selection

Nrate (RATE[15..0])		Fgen with 64 MHz Master Clock (Hz, or Samples per second: SPS)
(Dec)	(Hex)	
64	40	1,000,000
1280	500	50,000
---	---	Fgen (Hz) = 64,000,000 / Nrate

3.4.4.3 Generator Cascading

To obtain very low sampling or burst-triggering rates, the Rate-B generator can be configured with the RATE-B CLOCK SOURCE control field to operate from the output of the Rate-A generator instead of from the master clock. When operating in this *cascaded* configuration, the output frequency of the Rate-B generator is:

$$F_{\text{gen-B}} (\text{Hz}) = F_{\text{clk}} / (N_{\text{rate-A}} * N_{\text{rate-B}}) ,$$

which can produce sample rates as low as 0.015 Hz with $F_{\text{clk}} = 64$ MHz.

3.4.5 External Clock and Sync I/O

Multiple boards can be interconnected externally to produce synchronous analog input sampling and burst triggering. Figure 2.3-2 illustrates the interconnections required. One of the boards is designated as the *Initiator*, and the remaining boards are designated as *targets*.

A board that is enabled for external sync I/O is designated as a **clock target** by selecting 'External Clock Input Line' in the SAMPLE CLOCK SOURCE control field of the Scan and Sync control register. An external clock input signal can originate either from an initiator board, or from an independent TTL source. Any other value for this field designates the board as a **clock initiator**.

A **clock initiator** generates an output clock pulse in conjunction with each internal ADC sample clock, and each of the target boards responds to the clock pulse by acquiring a single sample of all of its designated active channels.

External **burst triggering** I/O is implemented in the same manner as external clocking I/O, but the trigger source is selected through the BURST ON SYNC control field in the Scan and Sync control register, and the SYNC I/O pin provides the external trigger interface connection.

NOTES: To avoid contention on the SYNC I/O and CLOCK I/O lines, no more than one board can be designated as sync or clock initiator.

For optimum autocalibration effectiveness at rates above 50 KSPS, adjust the Rate-A Generator register to the same value on all boards.

Refer to Paragraphs 3.9 and 3.15 for alternative external clock and sync provisions.

3.5 Analog Data Control

3.5.1 Input Data Organization

Processed conversion data from the analog-to-digital converters (ADC's) flows into the analog input FIFO data buffer, and from the data buffer to the PCI Express bus as analog input data. The data buffer appears to the bus as a single read-only register.

3.5.1.1 Input Data Buffer

Nonpacked analog input data is right-justified to the LSB, and occupies bit positions D00 through D15 (Table 3.5-1). D31 is the Channel-00 tag, which is asserted when the data field contains Channel-00 data. The Channel-00 tag is not available for packed data, nor when operating in the optional time-tagging mode (Appendix-C)

The intermediate bit field is all-zero unless two's complement coding is selected, in which case the reserved bits become the sign extension. When selection of active channels is user-defined (3.4.2.2), the context of the "Channel-00 tag" in the data buffer becomes the "First-Channel tag."

An empty buffer returns an indeterminate value. Refer to Paragraph 3-11 for the configuration of packed data, and for the effect of data packing on buffer contents.

Table 3.5-1. Input Data Buffer; Nonpacked Data

Offset: 0008h	Default: N/A		
	Channel-00 Tag	Reserved * (Zero)	Channel Data Value
Data Bit(s)	D[31]	D[30..16]	D[15..0]

All fields are read-only; Write-data is ignored.

3.5.1.2 Data Coding Format

Analog input data is arranged in a right-justified data field with the coding conventions shown in Table 3.5-2. The default format is offset binary. Two's complement format is selected by clearing the OFFSET BINARY control bit LOW in the BCR. Unless indicated otherwise, offset binary coding is assumed throughout this document.

Table 3.5-2. Input Data Coding

Analog Input Level	16-Bit Digital Value (Hex)	
	Offset Binary	Two's Complement
Positive Full Scale minus 1 LSB	FFFF	7FFF
Zero (Midscale)	8000	0000
Zero minus 1 LSB	7FFF	FFFF
Negative Full Scale	0000	8000

3.5.2 Input Data Buffer Control

The Input Data Buffer control register shown in Table 3.5-3 controls and monitors the flow of data through the analog input data buffer. Asserting the CLEAR BUFFER control bit HIGH clears, or empties, the buffer. The Threshold Flag is HIGH when the number of values in the input data buffer **exceeds the input threshold value** defined by bits D00-D17, and is LOW if the number is equal to or less than the threshold value. An interrupt (Section 3.7) can be programmed to occur on either the rising or falling edge of the threshold flag.

The Buffer Size register shown in Table 3.5-4 contains the number of locations occupied in the buffer, and is updated continuously. **If data packing is enabled and scan marking is disabled (3.11), the number of samples present in the buffer is twice the value contained in the Buffer Size register.**

Buffer underflow and overflow flags in the BCR indicate that the buffer has been read while empty or written to when full. Each of these situations is indicative of data loss. Once set HIGH, each flag remains HIGH until cleared, either by directly clearing the bit LOW or by clearing the buffer or initializing the board.

Table 3.5-3. Input Data Buffer Control Register

Offset: 000Ch

Default: 0003 FFEh

Data Bit	Mode	Designation	Def	Description
D00-D17	R/W	THRESHOLD VALUE	3 FFEh	Input buffer threshold value.
D18	R/W	CLEAR BUFFER *	0	Clears (empties) the input buffer and processing pipeline when asserted HIGH.
D19	RO	THRESHOLD FLAG	0	Asserted HIGH when the number of values in the input buffer exceeds the THRESHOLD VALUE.
D20-D31	RO	(Inactive)	0	---

*Clears automatically.

Table 3.5-4. Buffer Size Register

Offset: 0018h

Default: 0000 0000h

Data Bit	Mode	Designation	Def	Description
D00-D18	RO	BUFFER SIZE	00000h	Number of locations occupied in the input buffer
D19-D31	RO	(Inactive)	0	---

3.5.3 Analog Input Function Modes

BCR control field AIM[] selects the analog input signal source, and provides selftest modes for monitoring the integrity of the analog input networks. Table 3.5-5 summarizes the input function modes.

Table 3.5-5. Analog Input Function Selection

AIM[2:0]	Function or Mode
0	System analog input mode (Default mode).
1	(Reserved)
2	ZERO test. Internal ground reference is connected to all analog input channels.
3	+VREF test. Internal voltage reference is connected to all analog input channels.
4-7	(Reserved)

3.5.3.1 System Analog Inputs

With the default value of 'Zero' selected for the AIM[] field in the BCR, all ADC channels are connected to the system analog inputs from the system I/O connector.

3.5.3.2 Selftest Modes

In the selftest modes, the analog input lines from the system I/O connector are ignored and have no effect on selftest results. Specified board accuracy applies to all selftest measurements, and the averaged values of multiple samples should be used for critical measurements.

The ZERO selftest applies a Zero reference signal to all input channels, and should produce a nominal midscale reading of 0000 8000h for 16-Bit offset binary data.

For the +VREF test, a precision reference voltage is applied to all inputs. The +VREF reference voltage equals 99.900% of the positive fullscale value (nominally 0000 FFDFh for 16-Bit data).

3.6 Autocalibration

To obtain maximum measurement accuracy, autocalibration should be performed after:

- Power warmup or a bus reset,
- Input range change,
- Sample rate change, if greater than 50 kHz.

Autocalibration is invoked by setting the AUTOCAL control bit HIGH in the BCR, and the control bit returns LOW automatically at the end of autocalibration. Autocalibration can be invoked at any time, and has a duration of approximately 2.0 seconds. Completion of the operation can be detected either by selecting the 'Autocalibration Operation Completed' interrupt condition (paragraph 3.7) and waiting for the interrupt request, or by simply waiting a sufficient amount of time to ensure that autocalibration has been completed.

A small error can be introduced when the input range is changed, or when a large change occurs in the sample rate. Performing autocalibration with the required sample rate selected eliminates this error. During autocalibration, no control settings are altered and external analog input signals are ignored.

NOTE: Time Tagging must be disabled during Autocalibration. If Time Tagging is enabled when Autocalibration is initiated, the ENABLE TIME TAG OPERATION control bit in the BCR will be cleared automatically.

To compensate for component aging, and to minimize the effects of temperature on accuracy, the autocalibration function determines the optimum calibration values for current conditions, and stores the necessary correction values in volatile memory. If a board is defective, the autocalibration process may be unable to successfully calibrate the inputs. If this situation occurs, the AUTOCAL PASS status bit in the BCR is cleared LOW at the end of the autocalibration interval, and remains LOW until a subsequent initialization or autocalibration occurs. AUTOCAL PASS is initialized HIGH, and remains HIGH unless an autocalibration failure occurs.

NOTE: The autocalibration utility uses the contents of the Rate-A generator control register to establish the ADC sample rate used during test-signal acquisition. For optimal calibration effectiveness when clocking the inputs from a source other than the Rate-A generator, adjust the Rate-A generator control register to approximately the value that would produce the expected sample rate (Section 3.4.4).

3.7 Interrupt Control

In order for the board to generate a PCI Express interrupt, *both* of the following conditions must occur:

- a. The internal controller must generate a Local Interrupt Request
- b. *PCI Express interrupt emulation* must be enabled.

If the internal controller generates a local interrupt request, a PCI Express interrupt will not occur unless the PCI Express interrupt has been enabled.

3.7.1 Local Interrupt Request

The Interrupt Control Register shown in Table 3.7-1 controls the single local interrupt request line. Two simultaneous source conditions (IRQ 0 and 1) are available for the request, with multiple conditions available for each source. IRQ 0 and 1 are logically OR'd together to produce the single interrupt available to the board.

When one or more selected conditions occur for either of the IRQ's, a local interrupt request is generated and the associated IRQ REQUEST flag bit is set HIGH. The request remains asserted until the PCI bus clears the request flag. A local interrupt request is generated automatically at the end of initialization, through IRQ0.

Interrupt conditions are *edge-sensitive*, and an interrupt request is generated if a selected interrupt condition undergoes a *transition* from 'false' (not-true) to 'true' while that condition is selected.

3.7.2 Enabling the PCI Express Interrupt

A local interrupt request will not produce an interrupt on the PCI Express bus unless interrupt emulation is enabled. Refer to the PEX-8311 reference manual for details pertaining to this function

Table 3.7-1. Interrupt Control Register

Offset: 0000 0004h

Default: 0000 0008h

Data Bit	Mode	Designation	Def	Value	Interrupt Event
D00-02	R/W	IRQ0 A0,1,2	0	0	Initialization completed.
				1	Autocalibration operation completed
				2	Input sample initiated (Sync)
				3	Input sample completed (data ready)
				4	Triggered burst initiated (BURST BUSY => HI)
				5	Triggered burst completed (BURST BUSY => LO)
D03	R/W	IRQ0 REQUEST	1*	---	Group 0 interrupt request flag. Set HIGH when the selected interrupt condition occurs. Clears the request when cleared LOW by the bus.
D04-06	R/W	IRQ1 A0,1	0	0	Idle; no interrupt condition selected.
				1	Input buffer threshold LOW-HIGH transition
				2	Input buffer threshold HIGH-LOW transition
				3	Input buffer overflow or underflow
				4-7	(Reserved)
D07	R/W	IRQ1 REQUEST	0	---	Group 1 interrupt request flag. See D03.
D08-31	RO	(Inactive)	0	---	

* HIGH after reset.

3.8 DMA Operation

DMA transfers from the analog input FIFO buffer are supported in either **block-mode** or **demand mode**, with the board operating as bus master. Demand mode operation requires the **slow terminate** mode. Refer to the PEX-8311 reference manual for a detailed description of the associated DMA configuration registers.

NOTE: The PEX-8311 adapter extracts data from the 32-Bit (Lword) local bus in 64-Bit (quad-word) increments. Consequently, *if the buffer runs empty or nearly empty*, the situation can arise in which the last one or two samples in an active channel group are retained until subsequent data is acquired by the host. If this occurs, the next sample set flushes the retained data through the PEX-8311 adapter to the PCI Express bus, and no samples are lost.

3.9 Auxiliary External Clock and Sync I/O

Two auxiliary external connections provide an alternate method of synchronizing sample clocking and burst triggering to external events. These bidirectional TTL connections are available as AUX CLOCK and AUX SYNC (Table 2.2-2), and when active as *inputs*, replace the corresponding external CLOCK I/O and SYNC I/O inputs in the system I/O connector. The AUX I/O signals are accessible through a 6-Pin connector on the back (Side-2) of the board.

AUX clock and sync signals are designated independently through the Auxiliary Sync I/O Control register as inputs, outputs, or inactive, as indicated in Table 3.9-1. When an AUX signal is designated as an *input*, the signal replaces the corresponding CLOCK I/O or SYNC IO input from the system connector. In order for the input to be acknowledged, **target mode** must be selected in the corresponding clock or sync control field in the Scan and Sync control register (Table 3.4-2). The AUX I/O pins are pulled up internally to +3.3VDC through 4.7K.

Active AUX **outputs** produce an output pulse for each internal ADC sample clock or burst trigger, and are active in both target and initiator clock and sync modes.

To increase the reliability of external triggering in high-noise environments, selectable noise suppression increases the debounce or detection interval for active inputs, and increases the pulse width of active outputs.

AUX *inputs* are edge-detected as LOW-to-HIGH transitions if the INVERT INPUTS control bit is LOW, or as HIGH-to-LOW transitions if the bit is HIGH. Minimum HIGH and LOW level durations are 100ns if the NOISE SUPPRESSION control bit is LOW, or 1.5us if the bit is HIGH. AUX *output pulses* are positive (i.e.: baseline level is LOW) if the INVERT OUTPUTS control bit is LOW, or negative (baseline HIGH) if the control bit is HIGH. Output pulse width is typically 130ns if the NOISE SUPPRESSION control bit is LOW, or 2.0us if the bit is HIGH.

Table 3.9-1. Auxiliary Sync I/O Control

Offset: 0000 0034h

Default: 0000 0000h

Data Bit	Mode	Designation	Default	Description
D00-01	R/W	AUX CLOCK Control Mode	0	AUX CLOCK I/O Control Mode: 0 => Inactive 1 => Active Input (LO-to-HI edge) 2 => Active Output (Positive pulse) 3 => (Reserved)
D02-03	R/W	AUX SYNC Control Mode	0	AUX SYNC I/O Control Mode *
D04-05	R/W	(Reserved)	0	---
D06-07	R/W	(Reserved)	0	---
D08	R/W	INVERT INPUTS	0	Active inputs are detected on the LO-to-HI edge when this bit is LOW, or on the HI-to-LO edge when this bit is HIGH.
D09	R/W	INVERT OUTPUTS	0	Active outputs produce HIGH pulses when this bit is LOW, or LOW pulses when this bit is HIGH.
D10	R/W	NOISE SUPPRESSION **	0	When LOW, input debounce time is 85ns-110ns and output pulse width is 135ns. When HIGH, input debounce time is 1.5us, and output pulse width is 2.0us.
D11-31	RO	(Reserved)	0	Read-back as all-zero.

* Same configuration as the AUX CLOCK I/O control mode.

** Ignored for sync outputs if operating in Rate-B Sync Output mode. See 3.15

3.10 Board Configuration Register

The read-only board configuration register (Table 3.10-1) contains the existing firmware revision, and a status field that indicates the configuration of optional features.

Table 3.10-1. Board Configuration Register

Offset: 0000 0028h

Default: 00XX XXXXh

Bit Field	Description
D00-D11	Firmware Revision
D12-D15	(Reserved status flags or revision field).
D16-D17	Channel Availability: 0 => 32 Channels 1 => 16 Channels 2 => (Reserved) 3 => (Reserved)
D18-D19	Master Clock Frequency: 0 => 64.000 MHz 1-3 => (Reserved)
D20-D21	Custom Feature: 0-3 => (Reserved)
D22-D31	(Reserved)

3.11 Data Packing

Data packing enables the entire 32-Bit local bus to be used to convey data to the PCI Express bus. Setting the ENABLE DATA PACKING control bit high in the BCR selects the data packing mode, in which two consecutive 16-bit data values are packed into a single 32-Bit local data longword. In the data packing mode, a 32-bit scan marker code is inserted directly before each Channel-00 data value in the buffer (or immediately before the 'first channel' if the active channels are user-defined (3.4.2.2).

The scan marker can be disabled by setting the DISABLE SCAN MARKER control bit HIGH in the BCR.

Table 3.11-1. Data Packing

Buffer Lword Order	Buffer Data Field					
	ENABLE DATA PACKING = 0 DISABLE SCAN MARKER = X		ENABLE DATA PACKING = 1 DISABLE SCAN MARKER = 0		ENABLE DATA PACKING = 1 DISABLE SCAN MARKER = 1	
	D[31..16]	D[15..0]	D[31..16]	D[15..0]	D[31..16]	D[15..0]
00	8000h	Chan 00 Data	Upper Marker	Lower Marker	Chan 01 Data	Chan 00 Data
01	0000h	Chan 01 Data	Chan 01 Data	Chan 00 Data	Chan 03 Data	Chan 02 Data
02	0000h	Chan 02 Data	Chan 03 Data	Chan 02 Data	Chan 05 Data	Chan 04 Data
03	0000h	Chan 03 Data	Chan 05 Data	Chan 04 Data	Chan 07 Data	Chan 06 Data
---	---	---	---	---	---	---

The scan marker code is defined by the 'Scan Marker Upper Word' and 'Scan Marker Lower Word' registers listed in Table 3.1-1, and is inserted immediately before the first value in each data scan as shown in Table 3.11-1. The lower 16 bits in each register contains one word of the code. The upper 16 bits of these registers are ignored, and should be written as all-zero.

Some applications may require the scan marker code to be absolutely unique and not appear randomly in the data. To support this requirement, an all-zero marker code (0000 0000h) causes every all-zero data value (0000h) to be forced to a unit code (0001h) when data packing is enabled. This arrangement supports the uniqueness requirement without affecting the differential nonlinearity of the data itself.

NOTE: If the number of active channels is odd-numbered while data packing is enabled, an all-zero data value is inserted directly after the last active channel value. Like all other all-zero data values, the inserted value is forced to a unit code if an all-zero marker is in effect and scan marking is enabled.

3.12 Triggered Bursts

The BURST ON SYNC control field in the Scan and Sync control register (Tables 3.4-2 and 3.12-1) controls the triggering mode for acquisition bursts. Bursting is disabled if this field is zero. For all nonzero values, a sync event, or *trigger*, initiates a **burst** of internal sample clocks, each of which produces a sample of all active channels.

NOTE: The logic polarities of the external clock and sync I/O pins can be inverted by setting the INVERT CLOCK AND SYNC I/O control bit HIGH in the Scan and Sync control register (Paragraph 2.3.2 and Table 3.4-2). This inversion does not affect the Auxiliary Sync logic polarities selected in Table 3.9-1.

3.12.1 Burst Size and Trigger Source

The number of sample clocks issued during a burst is controlled by the 20-bit **Burst Size control register** listed in Table 3.1-1, which has a range from 1 to 1,048,575 sample clocks. For Burst-Size values of one or greater, the number of sample clocks in a burst equals the value in the register, and the number of samples acquired is the value in the Burst Size register times the number of active channels. For example, if a burst size of 10 is selected while 16 channels are active, then each burst will contain 160 sample values. Selection of the burst trigger source is summarized in Table 3.12-1. A Burst-Size of zero produces a burst that extends continuously until stopped, either by disabling the internal clock or by clearing the BURST ON SYNC control field.

The Sync I/O pin in the system I/O connector can operate as an input or output trigger pin. The trigger output can serve as a burst trigger for target boards in which the BURST ON SYNC control field selects the external Sync I/O pin as a trigger source.

NOTE: During a triggered burst the BURST BUSY status flag in the Scan and Sync control register goes HIGH at the trigger event, and returns LOW at the end of the burst. Either edge of the BURST BUSY flag is selectable as an interrupt event (Table 3.7-1).

Table 3.12-1. Burst Trigger Source

Scan and Sync Register BURST ON SYNC	Burst Trigger Source	Sync I/O Pin
0	Bursting disabled.	Input (Disabled)
1	Rate-B generator.	Trigger Output
2	External Sync I/O input pin (or AUX input)	Trigger Input (Target mode)
3	INPUT SYNC control bit in the BCR.	Trigger Output

3.12.2 Sample Clock Source

When operating in the triggered-burst mode, the sample-clock source is selected by the SAMPLE CLOCK SOURCE field in the Scan and Sync control register.

The following sequence illustrates the setup for a typical burst operation, and assumes that ADC clocking is disabled:

1. Select the input range, sample-clock source and burst size, with clocking disabled,
2. Use Table 3.12-1 to select the burst trigger source (enables burst triggering),
3. Load and enable the associated rate generators, if required,
4. Clear the input buffer,
5. Enable ADC sampling by setting the ENABLE CLOCKING control bit HIGH in the Scan and Sync control register.

NOTE: ADC sampling, or clocking, is disabled while the ENABLE CLOCKING control bit in the Scan and Sync control register is in the default LOW state. Sampling commences when this bit is set HIGH.

3.13 Settling Time Considerations

An abrupt change in the analog configuration generally is followed by a 'settling' interval during which the analog networks are transitioning to a new state, and during which specified performance is suspended. Abrupt changes include:

- A change in voltage range or sample rate,
- A major input step-change,
- Transitioning into or out of a selftest mode, or out of autocalibration,
- A system or local reset,
- Power application.

The settling time required to reestablish specified performance depends upon the type of disruption, and can vary from tens of milliseconds for a change in voltage-range, to as long as 10-15 minutes after the initial application of power. For *most* configuration changes other than the application of power, specified performance should resume after a settling interval of 20-100 milliseconds. Low-frequency filters will extend the settling interval by an amount that depends upon the filter characteristics. In general, the longest settling delay consistent with application requirements should be implemented.

3.14 Low Latency Data Access

The Low-Latency data array consists of 32 16-bit Acquisition Registers followed by 32 Holding Registers. During each ADC data acquisition sequence, the acquisition registers are loaded sequentially with calibrated ADC data as the data for each channel becomes available. When data has been loaded into the last acquisition register, all data values are transferred simultaneously into the holding registers. Two's complement coding and Data packing are not supported for Low-Latency data.

The Holding Registers are available as an array of 32 Lword registers, each containing 16-bit ADC data in the lower half of the Lword, located at local offsets 0100h through 017Ch. The holding registers are controlled through the Low Latency Control register shown in Table 3.14-1.

Table 3.14-1. Low Latency Control Register

Offset: 0000 0040h

Default: 0000 07C0h

Data Bit	Mode	Designation	Default	Valid Range	Description
D00-D05	R/W	HOLD CHANNEL	00h	00-1Fh ¹	Channel number designated to initiate data "Hold".
D06-D11	R/W	RELEASE CHANNEL	1Fh	00-1Fh ¹	Channel number designated to release data 'Hold'.
D12-D31	RO	(Reserved)	0	0	Inactive. Returns all-zero.

¹ Data is not automatically constrained. Values outside this range will produce indeterminate results.

Reading the channel designated as the HOLD CHANNEL initiates a 'Data-On-Hold' state in which the holding data registers are no longer updated from the acquisition registers, and in which the last data sample set is 'locked' into the holding registers. Holding register data remains locked until data is read from the channel designated as the RELEASE CHANNEL, which releases the holding registers and allows data transfer from the acquisition registers to resume. Low-Latency data is accessible with 'single-read' transfers (DMA is not supported).

The DATA ON HOLD" status flag in the BCR is asserted HIGH while the register array is in the 'Data-On-Hold' state. The Low Latency mode does not affect any other board functions, all of which operate independently of the low latency mode.

There is no restriction on whether the Release channel is greater or less than the Hold channel. However, if the HOLD and RELEASE channel values are equal, reading the common value will not initiate a data-hold, nor will reading any channel initiate a data-hold.

3.15 Rate-B Sync Output

Setting the RATE-B SYNC OUTPUT control bit HIGH in the Scan and Sync control register (a) routes the output of the Rate-B generator as a TTL output pulse to the SYNC I/O pin in the system I/O connector and to the internal Auxiliary Sync I/O connector, and (b) connects the input of the RATE-B generator either to the output of the Rate-A generator which supplies the sampling clock for the ADCs, or to the sample clock itself. The intent of this feature is the provision of a marker pulse that represents "N" number of input sample clocks, where "N" equals the value written to the Rate-B Generator control register listed in Table 3.1-1. A single output pulse of 150-200ns width is produced every "Nth" ADC sample clock or Rate-A generator clock, where "N" has a valid range of 2-65535.

The output pulse commences approximately 60-90ns after the leading edge of the sample pulse or the Rate-A generator clock, depending upon which is selected. When the RATE-B SYNC OUTPUT control bit is HIGH, burst triggering is disabled, and the value of the BURST ON SYNC field in the Scan and Sync control register is ignored. The effects of the RATE-B SYNC OUTPUT selection on this and other control fields in the Scan and Sync control register, and in the Auxiliary Sync I/O control register, are summarized in Tables 3.15-1 and 3.15-2.

The default clocking source for the Rate-B generator when operating in the 'Rate-B Sync Output' mode is the ADC sample clock. To change the source to the Rate-A generator, set the RATE-B CLOCK SOURCE control bit HIGH in the Scan and Sync control register

Table 3.15-1. Scan and Sync Control Fields Affected by Rate-B Sync Mode

Offset: 0000 0020h

Default: 0000 0005h

Bit	Mode	Designation	Def	Description
D06	R/W	RATE-B SYNC OUTPUT	0	Provides the output of the Rate-B generator as an external output pulse, and drives the Rate-B generator either from the output of the Rate-A generator or from the sample clock. Over-rides the Burst-On-Sync selection.
D07	RO	BURST BUSY	0	Disabled
D08-D09	R/W	BURST ON SYNC	0h	Disabled; Bursting disabled.
D10	R/W	RATE-B CLOCK SOURCE	0	Selects the clock input source for the Rate-B generator: 0 => ADC Sample Clock. 1 => Rate-A generator output.

Table 3.15-2. Auxiliary Sync I/O Control Fields Affected By Rate-B Sync Mode

Offset: 0000 0034h

Default: 0000 0000h

Bit	Mode	Designation	Def	Description
D10	R/W	NOISE SUPPRESSION	0	Disabled for Sync Output. The Auxiliary Sync output pulse has the same width as the SYNC I.O output pulse in the system I/O connector.

SECTION 4.0

PRINCIPLES OF OPERATION

4.1 General Description

Each of 32 differential analog input channels contains a dedicated 16-Bit ADC, a selftest input switching network, and a differential input amplifier (Figure 4.1-1). A PCI Express interface adapter provides the interface between the controlling PCI bus and an internal local controller. +3.3VDC and +12VDC power from the bus is converted into regulated power voltages for the internal analog networks.

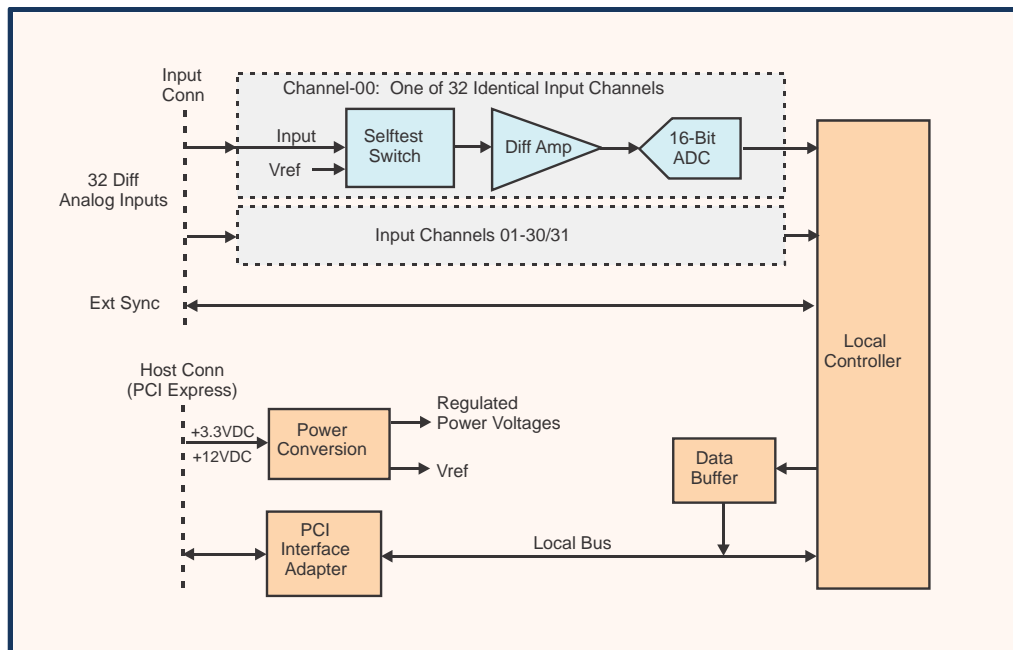


Figure 4.1-1. Functional Block Diagram

Selftest switches at the inputs provide test signals for autocalibration of all input channels. The input range is controlled by adjusting the gain of the differential amplifier. Each input sample is corrected for gain and offset errors with calibration values determined during autocalibration. A 1-Megabyte FIFO buffer accumulates analog input data for subsequent retrieval by an XMC host.

Analog input sampling on multiple target boards can be synchronized to a single software-designated initiator board. An interrupt request can be generated in response to selected conditions, including the status of the analog input data buffer.

4.2 Analog Inputs

Analog-to-digital conversions can be performed on signals from any of several sources, which are selected by the selftest switches shown in Figure 4.1-1. During normal operation, the ADC's receive system analog input signals from the input connector. For selftest and autocalibration operations, the internal voltage reference can be routed through the selftest switches to the ADC.

Serial data from all ADCs are deserialized simultaneously and then multiplexed into a parallel data pipeline within the local controller. The output of the multiplexer passes through a digital processor that applies gain and offset correction values obtained during autocalibration. The corrected data is then formatted and loaded into the analog input data buffer.

The inputs can be acquired either continuously or in discrete bursts. Burst triggers can be obtained from various sources, including an external Sync input I/O pin or by a 16-bit divider driven by the internal master clock. The number of samples in a burst is controlled by a Burst Size register.

4.3 Rate Generators

The local controller contains two independent rate generators, A and B, each of which divides a master clock frequency by a software-controlled 16-bit integer. The Rate-A generator provides the input sample clock by default, and the Rate-B generator usually is dedicated to generating triggered-burst triggers. The generators can be cascaded to produce very long sampling or burst intervals.

4.4 Data Buffer

A 1M-Byte FIFO buffer accumulates analog input data for subsequent retrieval by the PCI Express bus. The buffer is supported by a 'size' register that tracks the number of values in the buffer, and by a threshold flag that can be used to generate an interrupt request when the number of values in the buffer moves above or below a selected count. Local data packing is supported for 16-bit data, and DMA transfers can be implemented in both block and demand modes.

4.5 Autocalibration

Autocalibration is an embedded firmware utility that calibrates all analog input channels to a single internal voltage reference. The utility can be invoked at any time by the application software.

An internal voltage reference is used to calibrate the span of each channel, and a zero-reference is used to calibrate the offset value. Correction values determined during autocalibration are applied to each digitized sample as it is acquired during acquisition, and are retained until the autocalibration sequence is repeated, or until power is removed.

4.6 Power Control

Regulated supply voltages of ± 5 VDC and ± 14 VDC are required for internal analog networks, and are derived from the +3.3-Volt and +12-Volt inputs provided by the Host control bus, both by switching preregulators and by linear postregulators.

APPENDIX A

Local Control Register Quick Reference

APPENDIX A

Local Control Register Quick Reference

This appendix consolidates the local registers and principal control-bit fields described in Section 3.

Table 3.1-1. Control and Data Registers

Offset (Hex) ¹	Register	Access Mode ²	Default	Primary Function	Para Ref
0000	BOARD CONTROL (BCR)	RW	0000 4070h	Board Control Register (BCR)	3.2
0004	INTERRUPT CONTROL	RW	0000 0008h	Interrupt conditions and flags	3.7
0008	INPUT DATA BUFFER	RO	XXXX XXXXh	Analog input data buffer	3.5.2
000C	INPUT BUFFER CONTROL	R/W	0003 FFFEh	Input buffer threshold and control	
0010	RATE-A GENERATOR	RW	0001 0500h	Rate-A generator freq selection	3.4.4
0014	RATE-B GENERATOR	RW	0000 2000h	Rate-B generator freq selection	
0018	BUFFER SIZE	RO	0000 0000h	Number of values in the input buffer	3.5.2
001C	BURST SIZE	R/W	0000 0001h	Number of sample clocks in a triggered burst.	3.12.1
0020	SCAN AND SYNC CONTROL	R/W	0000 0005h	Channels per scan; Clock and Sync sources.	3.4.2
0024	ACTIVE CHANNEL ASSIGNMENT	R/W	0000 0100h	Specific first and last active channels.	3.4.2.2
0028	BOARD CONFIGURATION	RO	00XX XXXXh	Firmware revision and option straps.	3.10
002C	Autocal Values ³	R/W	0000 080Xh	Autocal value readback.	---
0030	Auxiliary R/W Register ³	R/W	0000 0000h	Auxiliary register. For internal use only.	---
0034	AUXILIARY SYNC I/O CONTROL	R/W	0000 0000h	Controls the auxiliary sync I/O port	3.9
0038	SCAN MARKER UPPER WORD	R/W	0000 0000h	Packed-data scan marker D[31..16].	3.11
003C	SCAN MARKER LOWER WORD	R/W	0000 0000h	Packed-data scan marker D[15..0].	
0040	Low Latency Control	R/W	0000 07C0h	Low Latency hold and release channels	3.14
0044-004C	(Reserved)	RO	0000 0000h	---	---
0050-00FC	Time Tag register field	---	---	---	App-C
0100-17C	Low-Latency Data	RO	0000 XXXXh	Low Latency data	3.14
0180-1FC	(Reserved)	RO	---	---	---

¹ Offsets from the PCI base address for local addressing.

² R/W = Read/Write; RO = Read-Only.

³ Maintenance register. Shown for reference only.

Table 3.2-1. Board Control Register (BCR)

Offset: 0000h

Default: 0000 4070h

Bit	Mode	Designation	Def	Description	Para Ref
D00-D02	R/W	AIM[2..0]	0	Analog input mode. Selects system inputs or selftest mode. Defaults to System Inputs	3.5.3.1
D03	R/W	(Reserved)	0	---	---
D04-D05	R/W	RANGE[1..0]	3h	Analog input range. Defaults to $\pm 10V$ range.	3.4.1
D06	R/W	OFFSET BINARY	1	Selects offset-binary analog I/O data format when asserted HIGH, or two's complement when LOW.	3.5.1.2
D07-D09	R/W	(Reserved)	0h	---	---
D10	RO	DATA ON HOLD	0	Low-Latency access status flag.	3.14
D11	R/W	DISABLE SCAN MARKER	0	Disables the scan marker in data packing mode.	3.11
D12	R/W	*INPUT SYNC	0	Produces a single ADC clock when selected in the Scan and Sync Control Register, or a single burst trigger when selected with the Burst On Sync control field.	3.12
D13	R/W	*AUTOCAL	0	Initiates an autocalibration operation when asserted.	3.6
D14	RO	AUTOCAL PASS	1	Set HIGH at reset or autocal initialization. A HIGH state after autocal completion confirms a successful calibration.	
D15	R/W	*INITIALIZE	0	Initializes the board when set HIGH. Sets all register defaults.	3.3
D16	R/W	BUFFER UNDERFLOW	0	Set HIGH if the buffer is read while empty. Cleared by direct write or by buffer clear.	3.5.2
D17	R/W	BUFFER OVERFLOW	0	Set HIGH if the buffer is written to when full. Cleared by direct write or by buffer clear.	
D18	R/W	ENABLE DATA PACKING	0	Enables local-bus data packing	3.11
D19	R/W	(Reserved)	0	---	---
D20	R/W	ENABLE TIME TAG OPERATION	0	Enables time tagging operations.	c1.1
D21-D31	RO	(Reserved)	0	---	---

* Clears automatically when the associated operation is completed.

Table 3.4-1. Analog Voltage Range Selection (BCR field)

Range Select[1:0]	Analog Input Range
0	$\pm 1.25V$
1	$\pm 2.5V$
2	± 5 Volts
3	± 10 Volts

Table 3.4-2. Scan and Sync Control Register

Offset: 0020h

Default: 0000 0005h

Bit	Mode	Designation	Def	Description
D00-D02	R/W	ACTIVE CHANNELS	5h	Number of active input channels: 0 => Single-Channel mode * 1 => 2 channels (00-01) 2 => 4 channels (00-03) 3 => 8 channels (00-07) 4 => 16 channels (00-15) 5 => 32 channels (00-31); Default value 6 => (Reserved) 7 => Channel group assignment (See Section 3.4.2.2) * Channel selected by Single-Channel Select field below.
D03-D04	R/W	SAMPLE CLOCK SOURCE	0h	Selects the analog input sample clocking source and I/O mode: 0 => External Clock input line (Selects Clock TARGET mode) 1 => Internal Rate-A generator output 2 => Internal Rate-B generator output 3 => BCR Input Sync control bit (If bursting disabled)
D05	R/W	ENABLE CLOCKING	0	Enables the selected ADC clocking process
D06	R/W	RATE-B SYNC OUTPUT	0	Provides the output of the Rate-B generator as an external output pulse, and drives the Rate-B generator either from the output of the Rate-A generator or from the sample clock. Over-rides the Burst-On-Sync selection. See 3.15.
D07	RO	BURST BUSY	0	Indicates that a triggered burst is in progress.
D08-D09	R/W	BURST ON SYNC	0h	Selects bursting trigger source and I/O mode (Section 3.12) 0 => Bursting disabled 1 => Rate-B generator 2 => External Sync-I/O input (Selects Sync TARGET mode) 3 => BCR Input Sync control bit.
D10	R/W	RATE-B CLOCK SOURCE	0	Selects the clock input source for the Rate-B generator: 0 => Master clock (or Sample Clock; See 3.15). 1 => Rate-A generator output.
D11	R/W	INVERT CLOCK AND SYNC I/O	0	Inverts the logic polarities of external clock and sync I/O input and output signals to assert HIGH.
D12-17	R/W	SINGLE-CHANNEL SELECT	0h	Selects the input channel number when operating in the Single-Channel scanning mode.
D18-D31	RO	(Reserved)	0	Inactive

Table 3.4-3. Active Channel Assignment

Offset: 0000 0024h

Default: 0000 0100h

Data Bit	Mode	Designation	Default	Description
D00-D07	R/W	FIRST CHANNEL SELECT	0	First (lowest-numbered) active channel
D08-D15	R/W	LAST CHANNEL SELECT	1	Last (highest-numbered) active channel
D16-D31	RO	(Reserved)	0	Inactive. Returns all-zero.

Table 3.4-4. Rate Generator Register

Offset: 0010h (Rate-A), 0014h (Rate-B)

Default: 0001 0500h (Rate-A), 0000 2000h (Rate-B)

Data Bit	Mode	Designation	Default	Description
D00-D15	R/W	NRATE	---	Rate generator frequency control
D16	R/W	GENERATOR DISABLE	1	Disables the rate generator when HIGH
D17-D31	RO	(Inactive)	0	---

Table 3.4-5. Rate Generator Frequency Selection

Nrate (RATE[15..0])		Fgen with 64 MHz Master Clock (Hz, or Samples per second: SPS)
(Dec)	(Hex)	
64	40	1,000,000
1280	500	50,000
---	---	$Fgen (Hz) = 64,000,000 / Nrate$

Table 3.5-1. Input Data Buffer; Nonpacked Data

Offset: 0008h

Default: N/A

	Channel-00 Tag	Reserved * (Zero)	Channel Data Value
Data Bit(s)	D[31]	D[30..16]	D[15..0]

All fields are read-only; Write-data is ignored.

Table 3.5-2. Input Data Coding

Analog Input Level	16-Bit Digital Value (Hex)	
	Offset Binary	Two's Complement
Positive Full Scale minus 1 LSB	FFFF	7FFF
Zero (Midscale)	8000	0000
Zero minus 1 LSB	7FFF	FFFF
Negative Full Scale	0000	8000

Table 3.5-3. Input Data Buffer Control Register

Offset: 000Ch

Default: 0003 FFFEh

Data Bit	Mode	Designation	Def	Description
D00-D17	R/W	THRESHOLD VALUE	3 FFFEh	Input buffer threshold value.
D18	R/W	CLEAR BUFFER *	0	Clears (empties) the input buffer and processing pipeline when asserted HIGH.
D19	RO	THRESHOLD FLAG	0	Asserted HIGH when the number of values in the input buffer exceeds the THRESHOLD VALUE.
D20-D31	RO	(Inactive)	0	---

*Clears automatically.

Table 3.5-4. Buffer Size Register

Offset: 0018h

Default: 0000 0000h

Data Bit	Mode	Designation	Def	Description
D00-D18	RO	BUFFER SIZE	00000h	Number of locations occupied in the input buffer
D19-D31	RO	(Inactive)	0	---

Table 3.5-5. Analog Input Function Selection (BCR field)

AIM[2:0]	Function or Mode
0	System analog input mode (Default mode).
1	(Reserved)
2	ZERO test. Internal ground reference is connected to all analog input channels.
3	+VREF test. Internal voltage reference is connected to all analog input channels.
4-7	(Reserved)

Table 3.7-1. Interrupt Control Register

Offset: 0000 0004h

Default: 0000 0008h

Data Bit	Mode	Designation	Def	Value	Interrupt Event
D00-02	R/W	IRQ0 A0,1,2	0	0	Initialization completed.
				1	Autocalibration operation completed
				2	Input sample initiated (Sync)
				3	Input sample completed (data ready)
				4	Triggered burst initiated (BURST BUSY => HI)
				5	Triggered burst completed (BURST BUSY => LO)
				6-7	(Reserved)
D03	R/W	IRQ0 REQUEST	1*	---	Group 0 interrupt request flag. Set HIGH when the selected interrupt condition occurs. Clears the request when cleared LOW by the bus.
D04-06	R/W	IRQ1 A0,1	0	0	Idle; no interrupt condition selected.
				1	Input buffer threshold LOW-HIGH transition
				2	Input buffer threshold HIGH-LOW transition
				3	Input buffer overflow or underflow
				4-7	(Reserved)
D07	R/W	IRQ1 REQUEST	0	---	Group 1 interrupt request flag. See D03.
D08-31	RO	(Inactive)	0	---	

* HIGH after reset.

Table 3.9-1. Auxiliary Sync I/O Control

Offset: 0000 0034h

Default: 0000 0000h

Data Bit	Mode	Designation	Default	Description
D00-01	R/W	AUX CLOCK Control Mode	0	AUX CLOCK I/O Control Mode: 0 => Inactive 1 => Active Input (LO-to-HI edge) 2 => Active Output (Positive pulse) 3 => (Reserved)
D02-03	R/W	AUX SYNC Control Mode	0	AUX SYNC I/O Control Mode *
D04-05	R/W	(Reserved)	0	---
D06-07	R/W	(Reserved)	0	---
D08	R/W	INVERT INPUTS	0	Active inputs are detected on the LO-to-HI edge when this bit is LOW, or on the HI-to-LO edge when this bit is HIGH.
D09	R/W	INVERT OUTPUTS	0	Active outputs produce HIGH pulses when this bit is LOW, or LOW pulses when this bit is HIGH.
D10	R/W	NOISE SUPPRESSION **	0	When LOW, input debounce time is 85ns-110ns and output pulse width is 135ns. When HIGH, input debounce time is 1.5us, and output pulse width is 2.0us.
D11-31	RO	(Reserved)	0	Read-back as all-zero.

* Same configuration as the AUX CLOCK I/O control mode.

** Ignored for sync outputs if operating in Rate-B Sync Output mode. See 3.15

Table 3.10-1. Board Configuration Register

Offset: 0000 0028h

Default: 00XX XXXXh

Bit Field	Description
D00-D11	Firmware Revision
D12-D15	(Reserved status flags or revision field).
D16-D17	Channel Availability: 0 => 32 Channels 1 => 16 Channels 2 => (Reserved) 3 => (Reserved)
D18-D19	Master Clock Frequency: 0 => 64.000 MHz 1-3 => (Reserved)
D20-D21	Custom Feature: 0-3 => (Reserved)
D22-D31	(Reserved)

Table 3.11-1. Data Packing

Buffer Lword Order	Buffer Data Field					
	ENABLE DATA PACKING = 0 DISABLE SCAN MARKER = X		ENABLE DATA PACKING = 1 DISABLE SCAN MARKER = 0		ENABLE DATA PACKING = 1 DISABLE SCAN MARKER = 1	
	D[31..16]	D[15..0]	D[31..16]	D[15..0]	D[31..16]	D[15..0]
00	8000h	Chan 00 Data	Upper Marker	Lower Marker	Chan 01 Data	Chan 00 Data
01	0000h	Chan 01 Data	Chan 01 Data	Chan 00 Data	Chan 03 Data	Chan 02 Data
02	0000h	Chan 02 Data	Chan 03 Data	Chan 02 Data	Chan 05 Data	Chan 04 Data
03	0000h	Chan 03 Data	Chan 05 Data	Chan 04 Data	Chan 07 Data	Chan 06 Data
---	---	---	---	---	---	---

Table 3.12-1. Burst Trigger Source

Scan and Sync Register BURST ON SYNC	Burst Trigger Source	Sync I/O Pin
0	Bursting disabled.	Input (Disabled)
1	Rate-B generator.	Trigger Output
2	External Sync I/O input pin (or AUX input)	Trigger Input (Target mode)
3	INPUT SYNC control bit in the BCR.	Trigger Output

Table 3.14-1. Low Latency Control Register

Offset: 0000 0040h

Default: 0000 07C0h

Data Bit	Mode	Designation	Default	Valid Range	Description
D00-D05	R/W	HOLD CHANNEL	00h	00-1Fh ¹	Channel number designated to initiate data "Hold".
D06-D11	R/W	RELEASE CHANNEL	1Fh	00-1Fh ¹	Channel number designated to release data 'Hold'.
D12-D31	RO	(Reserved)	0	0	Inactive. Returns all-zero.

¹ Data is not automatically constrained. Values outside this range will produce indeterminate results.

Table 3.15-1. Scan and Sync Control Fields Affected by Rate-B Sync

Offset: 0000 0020h

Default: 0000 0005h

Bit	Mode	Designation	Def	Description
D06	R/W	RATE-B SYNC OUTPUT	0	Provides the output of the Rate-B generator as an external output pulse, and drives the Rate-B generator either from the output of the Rate-A generator or from the sample clock. Over-rides the Burst-On-Sync selection.
D07	RO	BURST BUSY	0	Disabled
D08-D09	R/W	BURST ON SYNC	0h	Disabled; Bursting disabled.
D10	R/W	RATE-B CLOCK SOURCE	0	Selects the clock input source for the Rate-B generator: 0 => ADC Sample Clock. 1 => Rate-A generator output.

Table 3.15-2. Auxiliary Sync I/O Control Fields Affected By Rate-B Sync

Offset: 0000 0034h

Default: 0000 0000h

Bit	Mode	Designation	Def	Description
D10	R/W	NOISE SUPPRESSION	0	Disabled for Sync Output. The Auxiliary Sync output pulse has the same width as the SYNC I.O output pulse in the system I/O connector.

APPENDIX B
Migration From PMC66-16AI32SSC

Appendix B

Migration from PMC66-16AI32SSC

Operation of the CCVPX-16AI32SSC1M is very similar to that of the PMC66-16AI32SSC. This appendix summarizes the principal similarities and differences between the two products, and is provided as a general guide rather than a definitive list of requirements.

B.1. Comparison of Features

Table B.1 provides a brief comparison of PMC66-16AI32SSC and CCVPX-16AI32SSC1M features.

Table B.1. PMC66-16AI32SSC, CCVPX-16AI32SSC1M Features Comparison

Feature	PMC66-16AI32SSC	CCVPX-16AI32SSC1M
Number of Input Channels	32	32
Conversion Resolution	16 Bits	16 Bits
Native Input Configuration	Differential	Differential
Input Ranges	$\pm 10V$, $\pm 5V$, $\pm 2.5V$	$\pm 10V$, $\pm 5V$, $\pm 2.5V$, $1.25V$
Sample Rates	0-200KSPS	0-1MSPS
Time Stamp	Yes, Optional	Yes, Standard
Low Latency	Yes, Optional	Yes, Standard
Host Interface *	PCI 2.3; D32; 33MHz/66MHz	PCI Express, Single lane

* The host adapter (PEX-8311) provides the same local interface for both the CCVPX-16AI32SSC1M and PMC66-16AI32SSC products, thereby assuring a transparent software-control transition from PMC66-16AI32SSC to CCVPX-12AI32SSC1M.

B.2. Migration Issues

General:

1. The maximum sample rate has increased from 200KSPS to 1MSPS.
2. Low-Latency and Time-Tagging functions are now standard features.
3. The number of input ranges has increased from three to four.

Section 2.0. Installation and Maintenance:

Table 2.2-1:

Two sets of system pin assignments (a) and (b) have been replaced with a single compatible standard assignment. Four pins now have software-configured contexts.

Section 3.0. Control Software:

Tables 3.1-1 and 3.4-1:

BCR 'Range' field and default value have changed to accommodate an additional input range.

Paragraph 3.4.4.2, Table 3.4-5:

The maximum sample rate has increased to 1MSPS. The master clock frequency is now 64MHz.

Table 3.10-1:

Production options reflect functional changes.

Paragraph 3.14:

Adds low latency control register.

APPENDIX C

Time Tagging Operations

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APPENDIX C

TIME TAGGING OPERATIONS

c1.0 Introduction

Time tagging permits analog input data to be referenced to a software-controlled timebase. In this implementation, the timebase is represented by a 48-Bit time tag counter that is clocked or advanced by a 1.0 microsecond reference clock. The accumulated time tag count can be appended to an input data block as a header that contains the time tag count, as well as additional information pertaining to the size and structure of the data block.

NOTE: This appendix applies only if the ENABLE TIME TAG OPERATION control bit is asserted HIGH in the BCR (Table 3.2-1).

c1.1 Establishing Time Tag Operation

The Time Tag Operational mode is established by setting the ENABLE TIME TAG OPERATION control bit HIGH in the BCR shown in Table 3.2-1. When the time-tag operational mode is established, a block of registers dedicated to time tag operations extends the original register set described in Section 3 of this manual. The operations described in this appendix are applicable only when this control bit is HIGH. If the ENABLE TIME TAG OPERATION control bit is LOW, then this appendix does not apply, and all operations contained in Section 3 are in effect.

NOTE: While the time tag operational mode is enabled, the descriptions contained in this appendix supersede those for equivalent operations described in Section 3.

When the time-tag operational mode is enabled, the following control registers and control fields in the original register set described in Section-3 are ignored, and their functions are either omitted or replaced with equivalent time tag control registers.

Board Control Register (BCR);	Table 3.2-1:
DISABLE SCAN MARKER	
INPUT SYNC	
ENABLE DATA PACKING.	
Rate-B Generator;	Paragraph 3.4.4.
Burst Size Control Register;	Paragraph 3.12.
Scan and Sync Control Register;	Table 3.4-2.
Active Channel Assignment;	Paragraph 3.4.2.2.
Auxiliary Sync I/O Control;	Paragraph 3.9.
Scan Marker Upper Word;	Paragraph 3.11.
Scan Marker Lower Word;	Paragraph 3.11.

c1.2 External System I/O Signals

The following pins in the system I/O connector are associated with Time Tag operations:

- CLOCK RST INP (input),
- REF CLK INP (input),
- SAMP CLK INP (input),
- SAMP CLK OUT (output).

Logic levels for both inputs and outputs are low-voltage TTL (LVTTTL). All signals are asserted HIGH and pulled up internally to +3.3V through 33K.

c2.0 Time Tag Control

Time tag operations are controlled by the register set shown in Table c2-1. These registers represent an extension of the original field of control registers described in Section 3 of this manual, and are active only when operating in the Time Tag mode. The Time Tag Operational mode is invoked by setting the ENABLE TIME TAG OPERATION control bit HIGH in the BCR.

Table c2-1. Time Tag Control and Status Registers

Offset (Hex) ¹	Register	Mode	Default	Primary Function	Ref
0050	TIME TAG CONFIGURATION (TTC)	RW	0000 0000h	Primary control register for time-tag operations.	c2.1
0054	ACTIVE CHANNEL MASK	R/W	FFFF FFFFh	Active channel selection mask.	c2.2
0058	TIME TAG COUNTER LOWER	RO	XXXX XXXXh	Time tag counter lower 32 bits.	c2.5
005C	TIME TAG COUNTER UPPER	RO	0000 XXXXh	Time tag counter upper 16 bits.	c2.5
0060	TIME TAG RATE DIVIDER	R/W	0000 0002h	Rate divider Nrate_timetag for ADC clocking. Minimum valid value = 2.	c2.3
0064	BURST SIZE	R/W	0000 0001h	Number of samples acquired per channel after a trigger occurs.	c2.4.1.4
0068	CONSTANT REFERENCE MASK	R/W	0000 0000h	Selects 'constant' or 'automatically updated' reference values individually for each input channel.	c2.4.1.1
006C-007C	(Reserved)	RO	0000 0000h	---	---
0080	CHAN00_THRESHOLD/REFERENCE	R/W	4000 8000h	Reference (D00-15) and Threshold (D16-31) values assigned to each input channel. (Offset = 0080h + 4*Channel Number)	c2.4.1
0084	CHAN01_THRESHOLD/REFERENCE	R/W	4000 8000h		
0088	CHAN02_THRESHOLD/REFERENCE	R/W	4000 8000h		
008C-00F8	CHAN03_THRESHOLD/REFERENCE to CHAN30_THRESHOLD/REFERENCE	R/W	4000 8000h		
00FC	CHAN31_THRESHOLD/REFERENCE	R/W	4000 8000h		

¹ Offset from the PCI base address for local addressing.

c2.1 Time Tag Configuration Register (TTC)

Primary control of time tag operations takes place through the Time Tag Configuration (TTC) register shown in Table c2-2.

Table c2-2. Time Tag Configuration (TTC) Register

Offset: 0050h

Default: 0000 0000h

Bit	Mode	Designation	Def	Description	Ref
D00-01	R/W	ADC SAMPLE CLOCK SOURCE	0	Selects the source of the ADC sample clock: 0 => Internal Rate-A generator. 1 => External 'SAMP CLK INP' input line. 2 => External 'REF CLK INP' input line. 3 => (Reserved).	c2.3
D02	R/W	ENABLE ADC CLOCKING	0	Enables ADC sampling when HIGH. Disables sampling when LOW.	c2.4
D03	R/W	(Reserved)	0	---	---
D04	R/W	ENABLE REFERENCE TRIGGERING	0	Selects the reference-triggered mode when HIGH, or the free-running mode when LOW.	c2.4
D05	R/W	(Reserved)	0	---	---
D06	R/W	GLOBAL TRIGGERING	0	All active channels are logged after each trigger when this bit is HIGH, but only triggered channels are logged when LOW.	c2.4.1.3
D07	R/W	(Reserved)	0	---	---
D08	R/W	EXTERNAL REFERENCE CLOCK	0	Selects the external 'REF CLK INP' input line as the time-tag reference clock source when HIGH, or the internal rate generator when LOW.	c2.5.1
D09	R/W	RESET TIME TAG *	0	Unconditionally clears the time tag counter to zero when set HIGH.	c2.5.2
D10	R/W	EXTERNAL TIME TAG RESET	0	Selects the external input line 'CLOCK RST INP' as the source of the time tag counter reset when HIGH.	c2.5.2
D11	R/W	ENABLE TIME TAGGING	0	The time tag header is inserted when this bit is HIGH, or is omitted when LOW. Applies in all modes when the time-tag operational mode is invoked.	c2.6
D12-31	RO	(Reserved)	0	---	---

* Does not clear automatically. Not edge-detected. Must be written LOW.

c2.2 Active Channel Selection

The Active Channel Mask control register shown in Table c2-3 determines which input channels will be acquired or ignored during an acquisition sequence. A channel is designated as **active** by setting the corresponding ACQUIRE CHANNEL xx control bit HIGH, or as **inactive** by clearing the bit LOW. Active channels are sampled and logged into the data buffer during acquisition, while inactive channels are ignored and do not occupy space in the buffer.

Table c2-3. Active Channel Mask Register

Offset: 0054h

Default: FFFF FFFFh

Bit	Mode	Designation	Def	Description
D00	R/W	ACQUIRE CHANNEL 00	1	Each bit enables Channel_XX acquisition when set HIGH; or disables Channel_XX acquisition when cleared LOW. (Control-Bit number equals channel number)
D01	R/W	ACQUIRE CHANNEL 01	1	
D02	R/W	ACQUIRE CHANNEL 02	1	
D03-29	R/W	ACQUIRE CHANNEL 03-29	1	
D30	R/W	ACQUIRE CHANNEL 30	1	
D31	R/W	ACQUIRE CHANNEL 31	1	

c2.3 ADC Sample Clock

The ADC conversion sample clock can be obtained from any of the three sources listed in Table c2.2 under ADC SAMPLE CLOCK SOURCE. Setting this field to equal '1' or '2', selects the external SAMP CLK INP or REF CLK INP input pin respectively, as the source of the ADC sample clock.

If the ADC SAMPLE CLOCK SOURCE control field equals '0' (default), then the internal Rate-A generator supplies the sample clock. The ADC sample rate **F_{samp}** (Figure c2-1) is determined by the master clock frequency **F_{clk}**, and two integers **N_{rate_A}** and **N_{rate_timetag}** as:

$$F_{\text{samp}} = F_{\text{clk}} / (N_{\text{rate_A}} * N_{\text{rate_timetag}})$$

N_{rate_A} is the value contained in the control register RATE-A GENERATOR shown in Table 3.4-4, and N_{rate_timetag} is the 20-Bit value in the TIME TAG RATE DIVIDER control register listed in Table c2.1. F_{clk} has a standard value of **64.000MHz**, although other frequencies are available; see Table 3.10-1. With a 64MHz master clock frequency, the range of sample rates available with the Rate-A generator is 0.015Hz to 1.0MHz, in which the upper limit is determined by the A/D converters. **The minimum value for N_{rate_A} and N_{rate_timetag} is 2.**

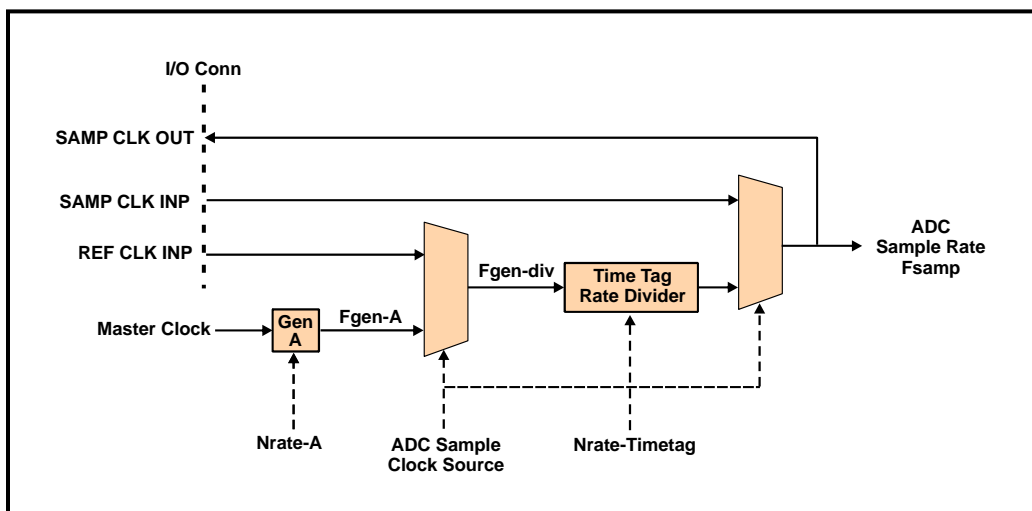


Figure c2-1. ADC Sample Rate Clock Source

For a 64MHz master clock frequency, **F_{samp}** is:

$$\mathbf{F_{samp} \text{ (kHz)} = 64,000 / (Nrate_A * Nrate_timetag).}$$

For example, Nrate_A and Nrate_timetag values of 2 and 1000 respectively would produce an ADC clocking frequency of 32.000kHz.

NOTE: The Rate-A generator can be disabled with a control bit in the associated control register (Table 3.4-4). This 'disable' control bit must be LOW in order for the internal rate generator to function.

If **REF CLK INP** is selected as the clock source, the ADC sample rate **F_{samp}** equals the frequency of the selected source divided by the 20-Bit integer **Nrate-timetag**. For the **SAMP CLK INP** source, the ADC sample rate **F_{samp}** equals the frequency of the source with no division involved, and simplifies the synchronization of ADC conversions on multiple boards.

When the ENABLE ADC CLOCKING control bit is high in the TimeTag Configuration register, the external output pin **SAMP CLK OUT** provides a 200 nanosecond positive pulse each time an ADC conversion occurs. SAMP CLK OUT is disabled if ENABLE ADC CLOCKING is LOW.

NOTE: For either external clock source input, REF CLK INP or SAMP CLK INP, the minimum time for both HIGH and LOW levels is 100 nanoseconds.

c2.4 Sampling Modes

The analog inputs can be sampled in either a continuous 'free running' mode or in triggered bursts. Triggered Burst sampling is selected when the ENABLE REFERENCE TRIGGERING control bit is HIGH in the TTC register, and Continuous sampling is selected when the control bit is LOW. In the Continuous sampling mode, sampling occurs as long as an active clock source is present and the ENABLE ADC CLOCKING control bit is HIGH. Time tagging can be applied in any sampling mode.

c2.4.1 Triggered Burst Sampling

When Triggered Burst sampling is selected, data is acquired in discrete bursts, and each burst is initiated by a specific Trigger event. A trigger event is determined by the amplitude of the data in each channel 'xx', and by the values of the following two software-assigned parameters:

- CHANNELxx Trigger Reference,
- CHANNELxx Trigger Threshold.

Both of these parameters are 16-Bit integers, and are assigned to each channel as indicated in Table c2-1. The reference and threshold values for each channel are contained in a single **CHANxx_THRESHOLD/REFERENCE** register (Table c2-4), with the Reference occupying the lower 16 bits and the Threshold occupying the upper 16 bits.

Table c2-4. Channel Reference/Threshold Control Register

Offset: 0080h + (4 * Channel Number)

Default: 4000 8000h

Bit	Mode	Designation	Def	Description
D00-15	R/W	CHANNELxx REFERENCE	8000h	Channel-XX trigger reference
D16-31	R/W	CHANNELxx THRESHOLD	4000h	Channel-XX trigger threshold

If time tagging is enabled, each sample clock latches the current value of the Time Tag counter for insertion into the buffer data header (c2.6).

NOTE: Trigger events that occur during a triggered burst are ignored. Also, an Interrupt can be generated in response to the initiation or termination of a triggered burst (Table 3.7-1).

c2.4.1.1 Constant Reference Triggering

Constant reference triggering is selected for each input channel by setting the associated CONSTANT REFERENCE VALUE control bit HIGH in the Constant Reference Mask control register (Table c2-5). In this mode, a trigger event occurs when the input data for the channel falls **outside** the range defined by the Channel Reference, plus or minus the Channel Threshold value.

That is; when:

Reference minus Threshold > Channel Trigger Amplitude > Reference plus Threshold,

or:

Amplitude < Reference minus Threshold => Trigger,

Amplitude > Reference plus Threshold => Trigger.

While Constant Reference triggering is selected, the assigned reference value is unaffected by a trigger event.

Because trigger-event detection is performed dynamically on a pipelined data stream, modifying a reference or threshold value during acquisition may cause an erroneous response for the ensuing sample.

Table c2-5. Constant Reference Mask

Offset: 0068h

Default: 0000 0000h

Bit	Mode	Designation	Def	Description
D00	R/W	CHAN-00 CONSTANT REFERENCE	0	The Channel-00 Reference value remains unchanged after each trigger when this bit is HIGH, or is updated automatically when LOW to equal the input level.
D01-D31	R/W	CHAN 01-31 CONSTANT REFERENCE	0	Same function as Bit D00, applied to Channels 01-31.

c2.4.1.2 Tracking Reference Triggering

If the CONSTANT REFERENCE VALUE control bit is LOW for a channel in the Constant Reference Mask control register, then **Tracking Reference triggering** is selected for that channel. This mode is identical to the Constant Reference triggering mode, except the reference value is now modified after each trigger event to re-center the triggering window around the trigger amplitude. The reference value is modified to equal the analog input data value.

c2.4.1.3 Triggering Scope

If the GLOBAL TRIGGERING control bit is LOW in the TTC register, then only those channels that experience a trigger event will be acquired during the ensuing burst. If the control bit is HIGH, then all active channels will be acquired during the burst, regardless of which channel or channels actually experienced a trigger.

NOTE: Multiple channels may experience a trigger condition simultaneously. In these instances, the data from all triggered channels will appear in the buffer.

c2.4.1.4 Triggered Burst Size

The number of samples acquired from each channel during a burst is referred to as a Sample Block, and is determined by the 16-bit Burst Size control register listed in Table c2-1, and by the number of active channels. For Burst-Size values of one or greater, the number of samples acquired from each input channel equals the value in the register. For example, if a burst size of 10 is selected while 16 channels are active during a burst, then the sample block will contain 160 sample values. A Burst-Size of zero produces a burst that runs continuously until stopped, either by disabling the sampling clock or by clearing the ENABLE REFERENCE TRIGGERING control bit.

NOTE: A "**Sample Block**" refers to all data associated with a single **burst trigger**. That is; all data acquired within a single burst.

A "**Sample Scan**" refers to the data acquired from all channels in response to a single **sample clock**.

c2.4.2 Continuous Sampling

When operating in the continuous 'free running' sampling mode, data is acquired continuously from all active channels as long as the input data buffer is not full, and if a valid sample clock is selected with the ADC SAMPLE CLOCK SOURCE control field in the TTC register. In this mode, input data accumulates in the buffer as shown in Table c2-6, but all active channels are represented.

c2.5 Time Tag Counter

The time tag value in the time tag header represents the accumulated count in a 48-bit counter that is advanced once per microsecond by a **1MHz reference clock**, and unless reset (c2.5.2), runs continuously while operating in the time-tagging mode. The entire 48-bit value is latched with each ADC sample clock to prevent rollover errors between the upper and lower bit fields in the data buffer header (c2.6). The latched value appears in the time tag header immediately before the ADC data from the associated sample clock, and is accessible also through the Lower and Upper Time-Tag registers listed in Table c2-1.

c2.5.1 Clock Source

The 1MHz reference clock for the time tag counter can be derived from an internal 1MHz generator, or from a 1 MHz external clock source. If the EXTERNAL REFERENCE CLOCK control bit is HIGH in the TTC register, the reference clock is obtained from the REF CLK INP pin in the system I/O connector. If this control bit is LOW, an internal 1 MHz generator provides the reference clock.

c2.5.2 Reset

The time tag counter can be cleared to zero at any time by asserting the RESET TIME TAG control bit in the TTC register, or by performing an initialization (3.3.2). The counter will remain cleared as long RESET TIME TAG is asserted. The counter can be cleared also from an external input through the CLOCK RST INP input pin in the system I/O connector when the EXTERNAL TIME TAG RESET control bit is set HIGH in the TTC register. If this control bit is LOW, the external CLOCK RST INP input is ignored.

c2.6 Data Buffer Configuration

A 48-Bit time tag counter provides a time reference for analog input data, and is included in a time tag header that can be appended to data as it is logged into the data buffer described in Section 3.5.1.1. The structure of the header is shown in Table c2-6. The MSB (D31) of the first longword in each header is set HIGH, to indicate the beginning of a new sample scan.

In addition to time tag information, the header also provides the number (**Nb**) of ADC samples contained in the ensuing sample scan.

The header is appended *in any mode* if the ENABLE TIME TAGGING control bit is HIGH in the Time Tag Configuration (TTC) register. If ENABLE TIME TAGGING is LOW, then the header is omitted and the buffer accumulates only sampled data with the channel number attached to each sample.

Sampled input data in the buffer commences immediately after the header, with the data value occupying the lower half bits of each longword, and the associated channel number located in the upper half. The Channel-00 flag shown in Table 3.5-1 is not applied when operating in the time-tag operational mode.

Table c2-6. Data Buffer Configuration

Buffer Lword Order	Segment	D[31..16]	D[15..0]	
0000	Header	8000h	Time Tag; Lower 16 Bits (D15..0]	First Sample Scan
0001		0000h	Time Tag; Intermediate 16 Bits (D31..16]	
0002		0000h	Time Tag; Upper 16 Bits (D47..32]	
0003		0000h	Nb; Number of ADC samples in first sample scan	
0004	Data	First channel number	First-channel data value	
---		Intermediate channel numbers	Intermediate channel data values	
Nb + 4		Last channel number	Last-channel data value	
---	Header	8000h	Time Tag; Lower 16 Bits (D15..0]	Second Sample Scan
---		0000h	Time Tag; Intermediate 16 Bits (D31..16]	
---		0000h	Time Tag; Upper 16 Bits (D47..32]	
---		0000h	Nb; Number of ADC samples in second sample scan	
---	Data	First channel number	First-channel data value	
---		Intermediate channel numbers	Intermediate channel data values	
---		Last channel number	Last-channel data value	
---	---	---	---	(Intermediate scans)
---	Header	8000h	Time Tag; Lower 16 Bits (D15..0]	Last Sample Scan
---		0000h	Time Tag; Intermediate 16 Bits (D31..16]	
---		0000h	Time Tag; Upper 16 Bits (D47..32]	
---		0000h	Nb; Number of ADC samples in last sample scan	
---	Data	First channel number	First-channel data value	
---		Intermediate channel numbers	Intermediate channel data values	
---		Last channel number	Last-channel data value	

c2.7 Data Coding Format

When operating in the time-tag mode, the data coding format described in Paragraph 3.5.1.2 applies to the 16-Bit channel data values in the Data buffer, and to the 16-Bit Reference and Threshold values listed in Table c2-4.

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General Standards Corp.
8302A Whitesburg Dr.
Huntsville, Alabama 35802
Telephone: (256) 880-8787
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